

SAMPIC-BASED SYSTEMS FOR INSTRUMENTATION WITH FAST DETECTORS

**D. Breton², C.Cheikali², E. Delagnes¹, H. Grabas^{1,3},
O. Lemaire², J. Maalmi², P. Rusquart², P. Vallerand²**

¹ CEA/IRFU Saclay (France)

² CNRS/IN2P3/LAL Orsay (France)

³ Now with SCICPP Santa Cruz (USA)



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The **TICAL** ERC project (grant number 338953 from EU; PI: Paul Lecoq) has also contributed to the developments of the TOT features integrated in the chip

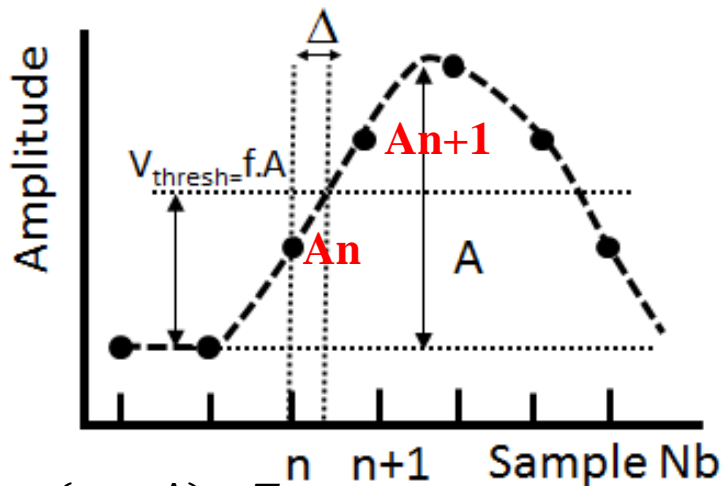
INTRODUCTION

- **Systems** based on a circuit : **SAMPIC**, dedicated to instrumentation with **fast detectors**. Can be **desktop-lab** solution as well as used for **large scale** detectors.
- What is SAMPIC? It is a full custom ASIC (LAL/IRFU) based on a new concept : Waveform-TDC
- We developed different types of **modules** based on this circuit.
- At LAL, we developed our own **protocol** and libraries for the **control and readout**, based on **USB** and **UDP** (copper or optical link)
- **Acquisition Software**: for **plug & play** systems
- Features and Performance of the circuit/modules
- Examples of application

The « Waveform TDC » Concept (WTDC)

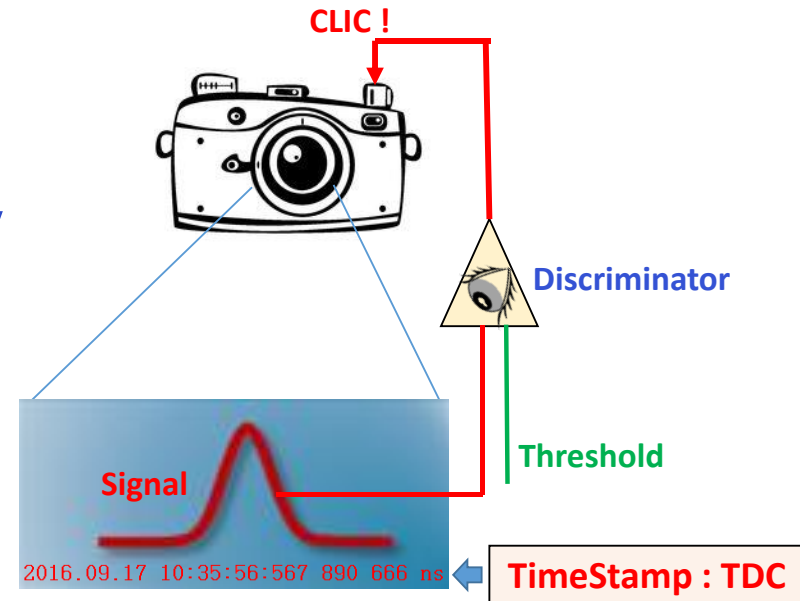
WTDC: a TDC which also permits taking a picture of the real signal. This is done via sampling and digitizing only the interesting part of the signal.

Based on the digitized samples, making use of **interpolation** by a digital algorithm, fine time information will be extracted.



$$t_0 = (n + \Delta) * T_s$$

$$\text{with } \Delta = \frac{f \cdot A - A_n}{A_{n+1} - A_n}$$



■ Advantages:

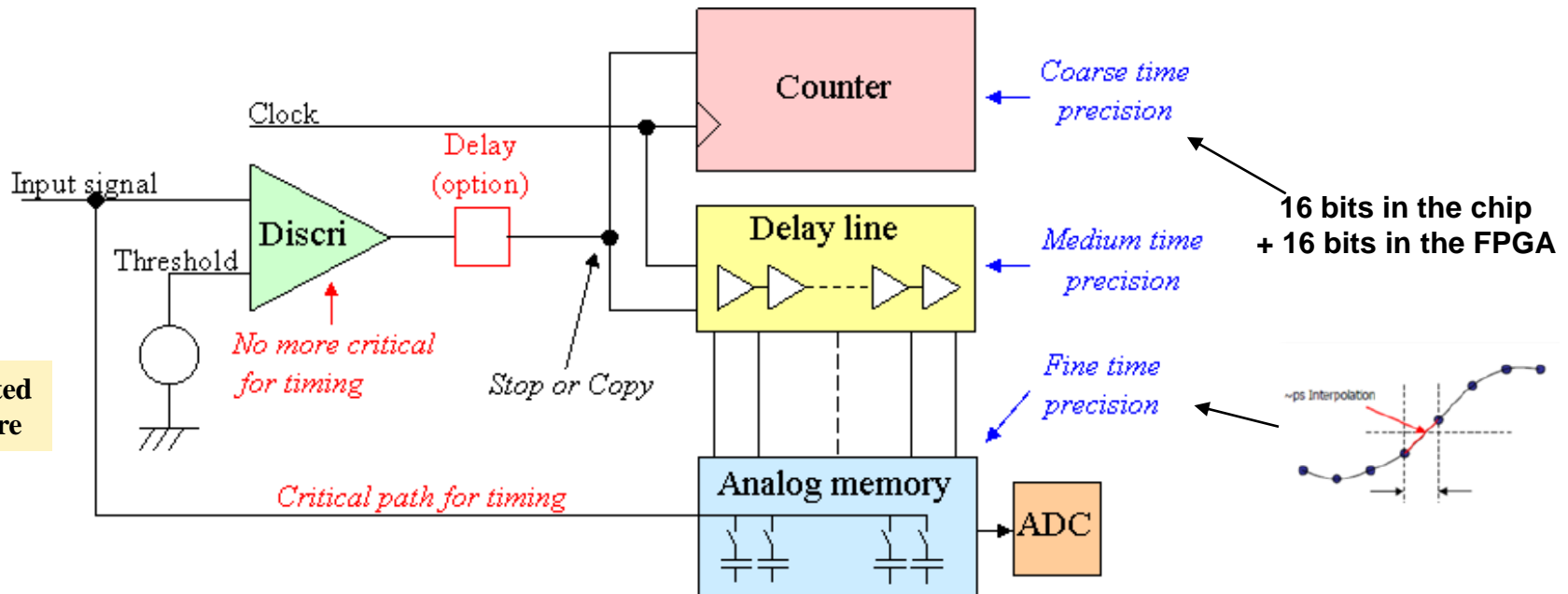
- Time resolution ~ few ps
- No “time walk” effect
- Possibility to extract other signal features: charge, amplitude...
- Reduced dead-time...

■ But:

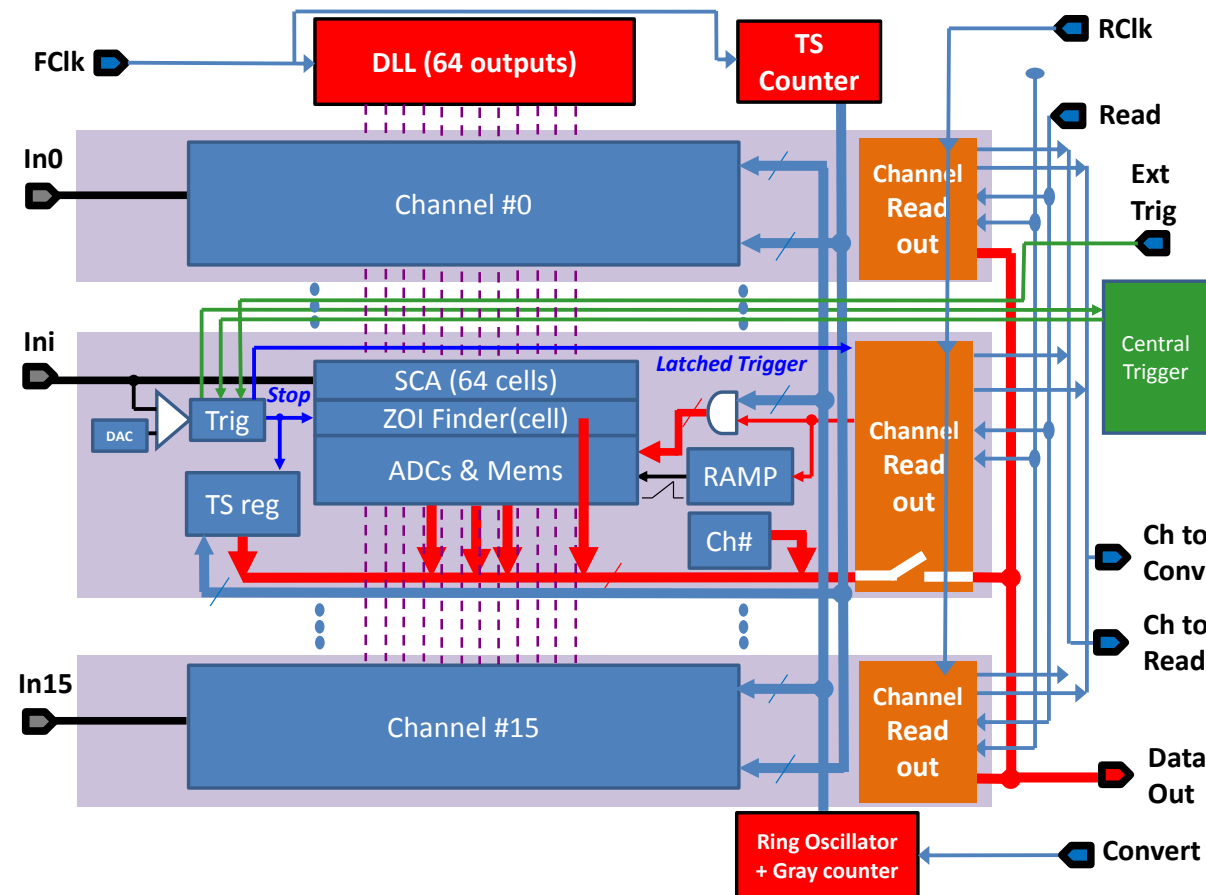
- waveform conversion (200 ns to 1.6 μ s) and readout times don't permit counting rates as high as with a classical TDC

THE « WAVEFORM TDC » STRUCTURE

- Mix of DLL-based TDC and of analog-memory based Waveform Digitizer
- The TDC gives the time of the samples and the samples give the final time precision after **interpolation** => **resolution of a few ps rms**
- Digitized **waveform** gives access to signal shape...
- Conversely to TDC, discriminator is used only for triggering, **not for timing**



Global architecture of SAMPIC



- **One Common 16-bit Gray Counter** (FClk up to 160MHz) for **Coarse Time Stamping (TS)**.

- **One Common servo-controlled DLL:** (from 0.8 to 8.5 GS/s) used for medium precision timing & analog sampling

- **16 independent WTDC channels each with :**

- ✓ 1 discriminator for self triggering
- ✓ Registers to store the timestamps
- ✓ 64-cell deep SCA analog memory
- ✓ One 11-bit ADC/ cell
(Total : 1024 on-chip ADCs)

- **One Central Trigger block**

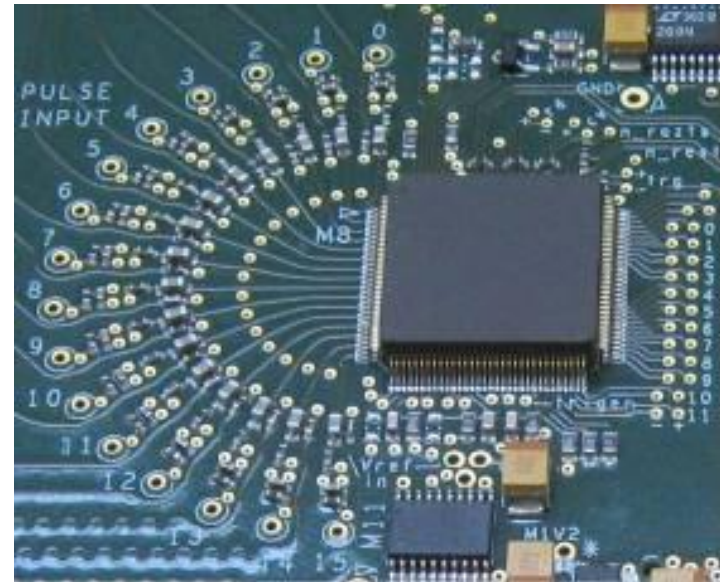
- **One common 1.3 GHz oscillator + counter** used as timebase for all the **Wilkinson A to D converters**.

- **Read-Out interface: 12-bit LVDS bus** running at > 160 MHz (> 2 Gbits/s)

- **SPI Link** for Slow Control

SAMPIC (V3)

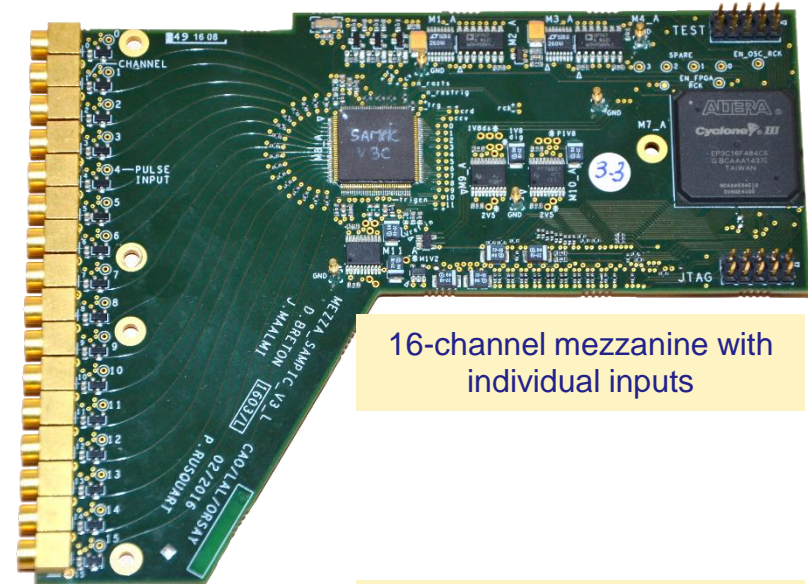
- Current version is V3 received in October 2017
- A new version with bug correction in case of saturation will be delivered soon



- Technology: **AMS CMOS 180nm**
- Surface: 8 mm²
- Package: QFP 128 pins, pitch of 0.4mm

FIRST SAMPIC MODULE

- First module developed is a 32-channel module integrating 2 mezzanines
 - This mezzanine has a “L” shape permitting the injection of **16 channels** via individual MCX connectors
 - 1 SAMPIC/mezzanine
-
- The motherboard is a multi-purpose standard board developed at LAL with USB2 & Gbit Ethernet UDP (RJ45 & Optical)
 - **32 channels** => 3 layers of boards

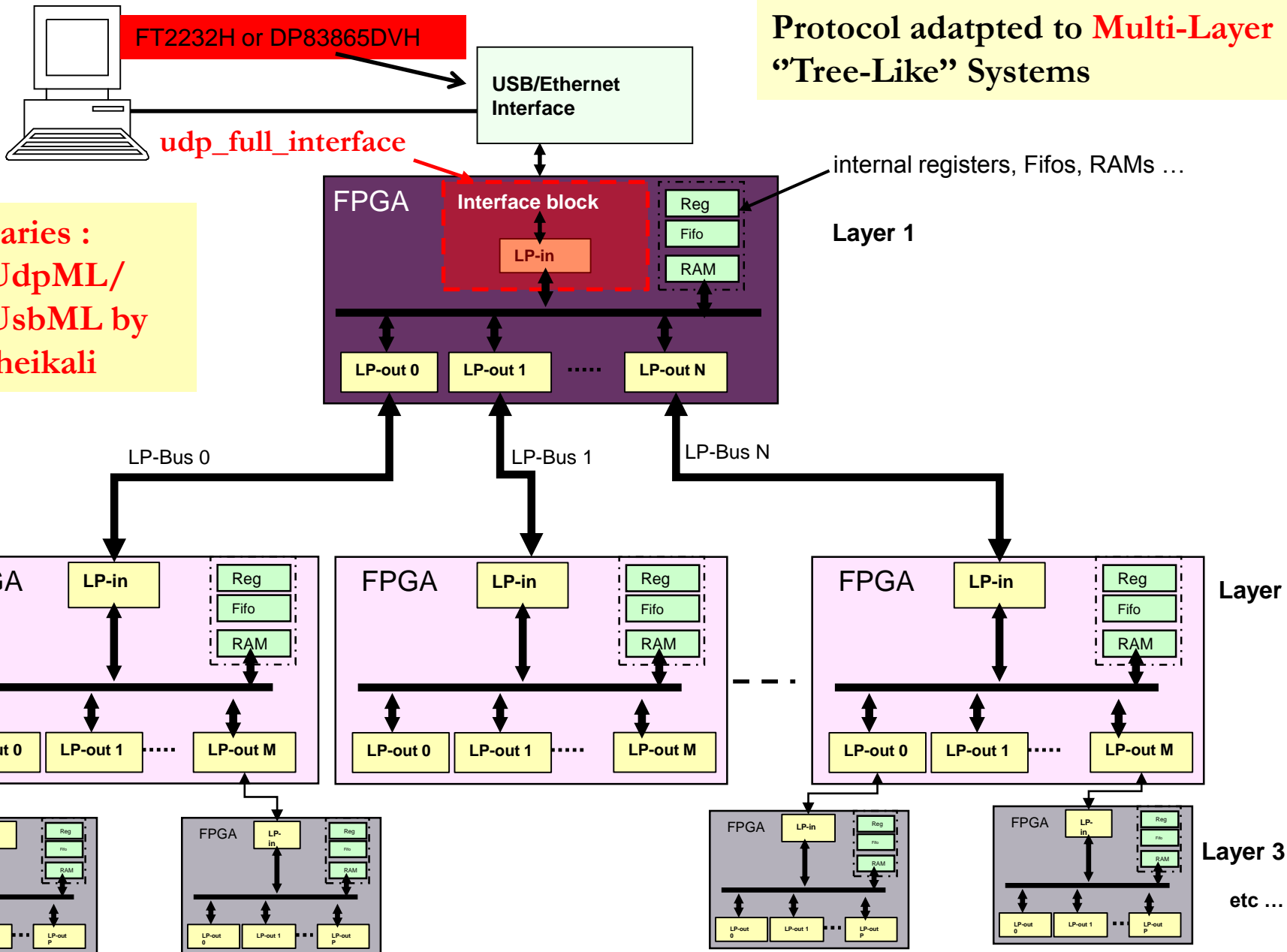


16-channel mezzanine with individual inputs

32-channel module



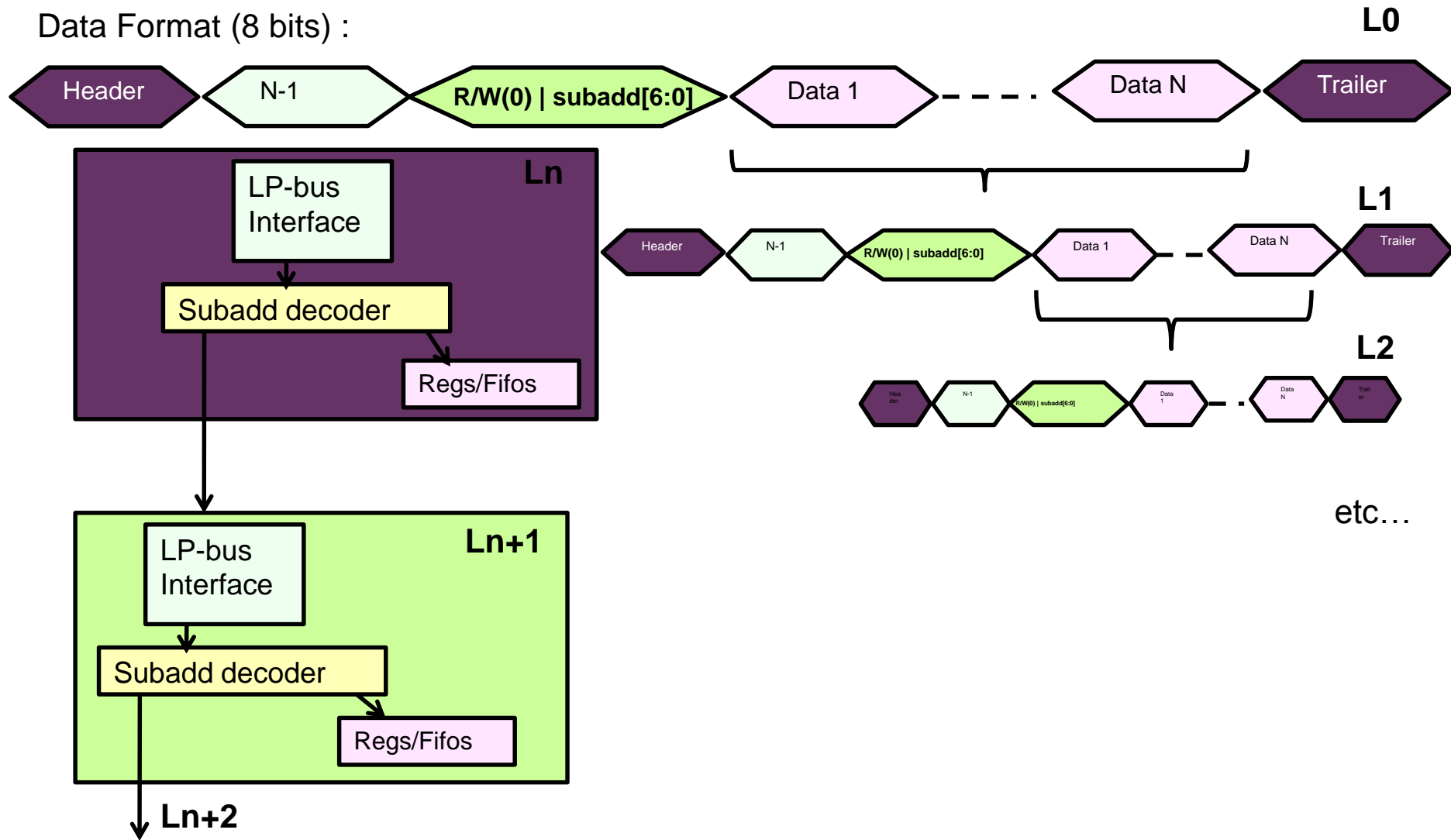
CONTROL/READOUT PROTOCOL: LP-BUS MULTI-LAYER



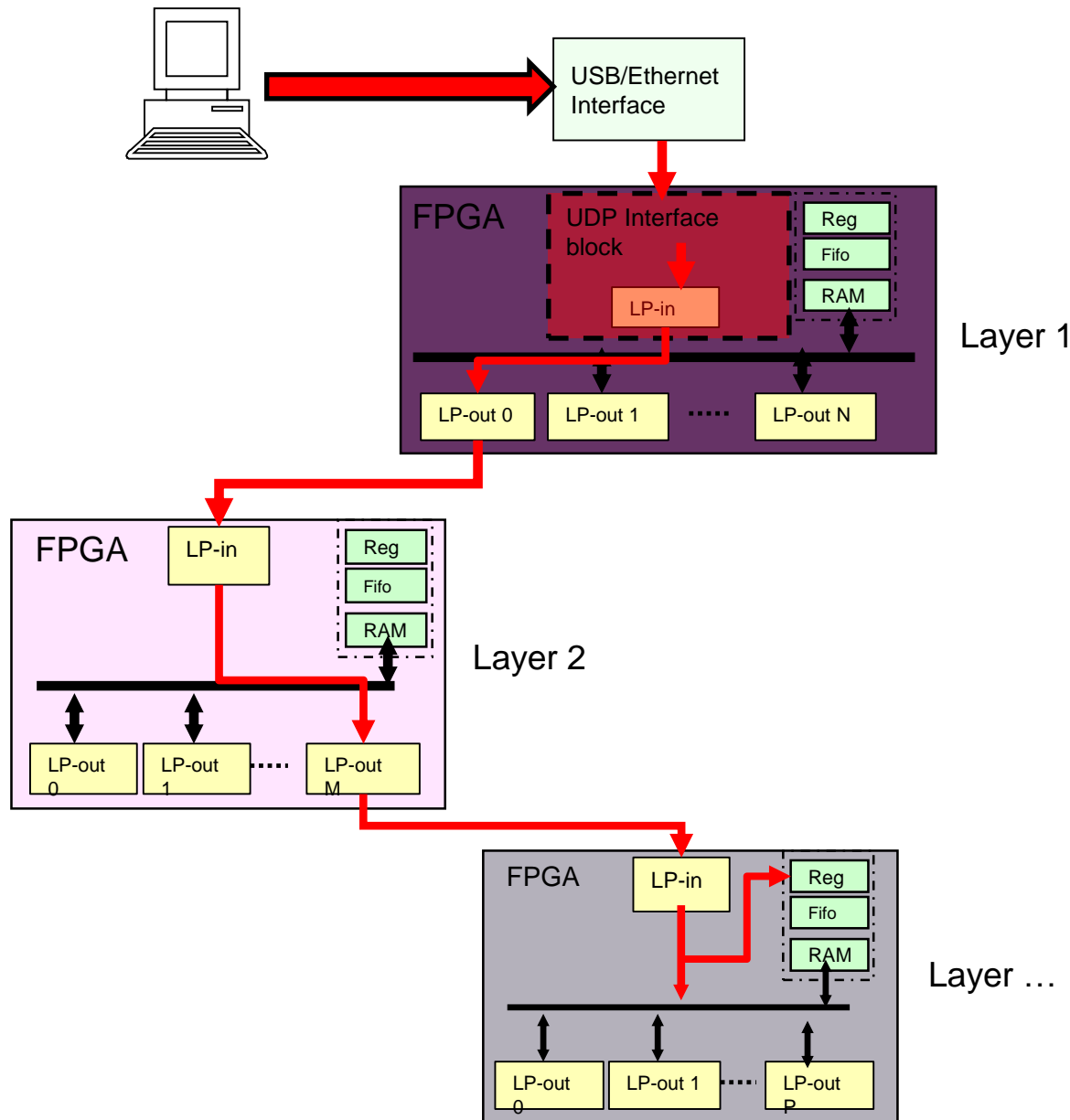
LOCAL PARALLEL BUS PROTOCOL

❖ « russian dolls » principle:

Data Format (8 bits) :



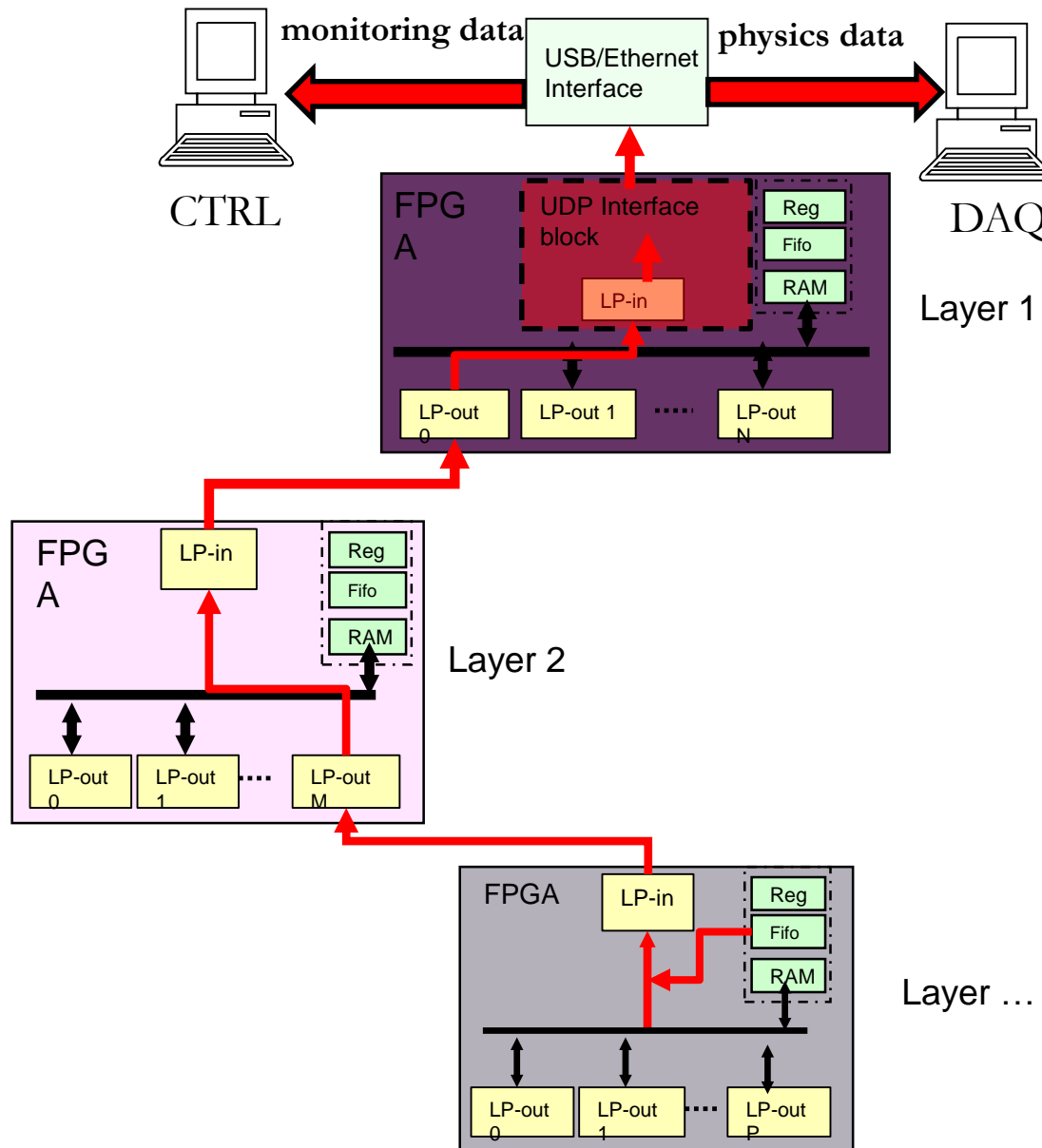
CONTROL ACCESS



LAL protocol « **Russian dolls** » control access:

- Frames are decapsulated at each layer
- Frames cross transparently each layer till the final destination.

READOUT ACCESS



« Russian dolls » LAL protocol, readout access:

- Frames are encapsulated at each layer.
- Data frames cross **transparently** each layer.
- While using UDP: Possibility to detect DAQ data and control Data and send them to two different ports.

RECENT MODULE DEVELOPMENTS

- In response to users' requests, we developed new modules and systems in order to **increase the number of channels**
- They make use of the new motherboard also developed for the **WaveCatchers**.
- **64-channel** modules and board are available.
- **256-channel** mini-crate is **under development** with new more integrated 64-channel boards.
- Acquisition through Gbit Ethernet UDP (RJ45 or Optical), **USB2** and soon **USB3**



256-channel mini-crate

64-channel module with individual inputs



64-channel module with flat cable inputs (can be digital or analog)

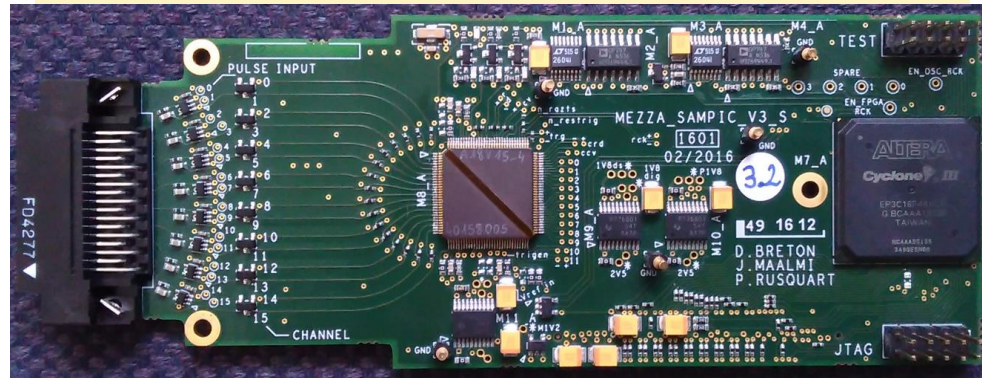


64-channel board with flat cable inputs (can be digital or analog)

DAUGHTERBOARD DEVELOPMENTS

- Various mezzanine cards have been developed for housing the new versions of the chip (including the digital differential option)
 1. Analog/digital input with MCX
 2. Analog/digital input with flat cable
 3. Differential digital input with flat differential cable
- Adaptors have also been developed

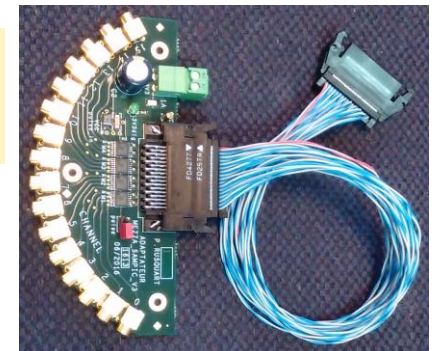
Mezzanine with flat cable analog/digital input



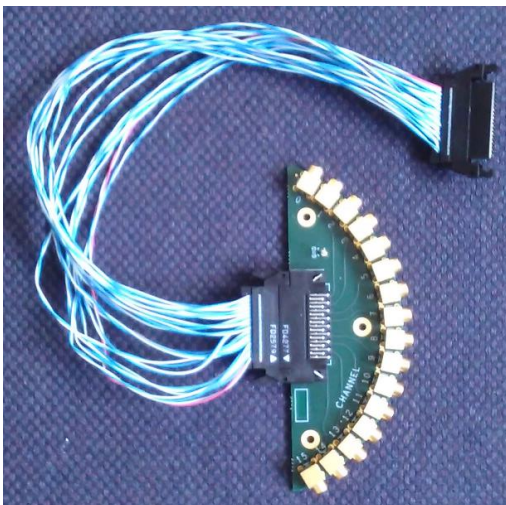
Mezzanine with flat cable differential digital input



16-channel individual to digital differential flat cable adaptor



16-channel individual to flat cable adaptor



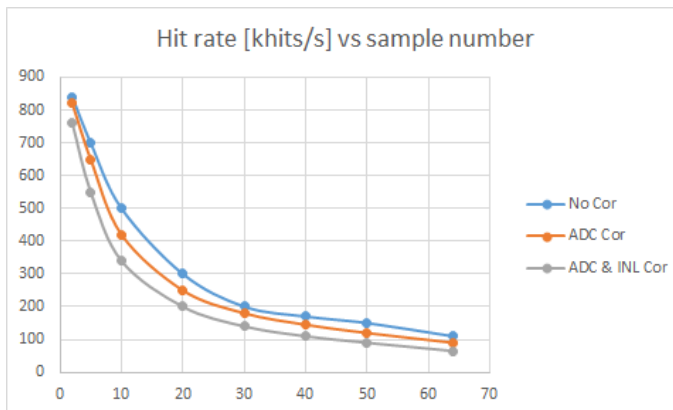
ACQUISITION SOFTWARE

- Acquisition software has been developed (& soon C libraries)

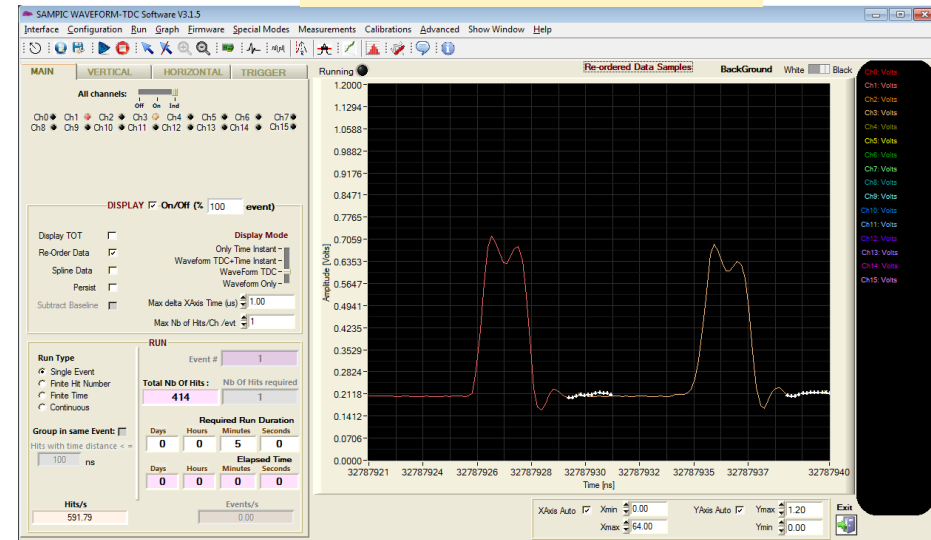
=> full characterization of the chip & module

- Special display for **WTDC mode**
- Data saving on disk.
- Used by all SAMPIC users.
- A smart panel dedicated to time measurement is available. It permits selecting the parameters used for **extraction of time**
 - Optional spline interpolation on the peak area and on the threshold area
 - Fixed threshold option
 - CFD: ratio, nb of applied thresholds (1 to 3)

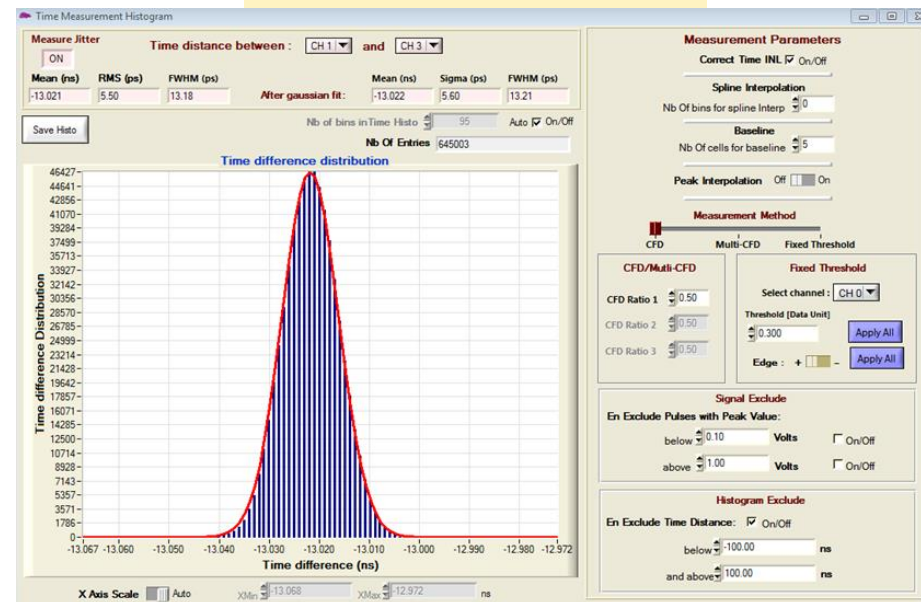
- **Recorded hit rate** depends on: the number of waveform samples, the corrections applied (ADC, Time INL), the saving on disk mode (ASCII, binary)...



Main panel



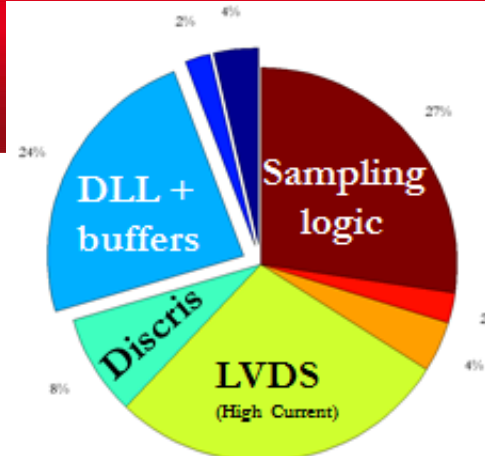
Time Measurement panel



SAMPIC GLOBAL PERFORMANCES

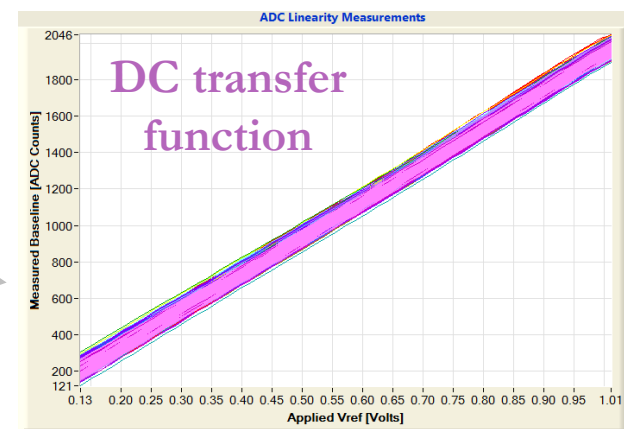
- Power consumption: **10mW/channel** →
- 3dB bandwidth > **1 GHz**
- Discriminator noise ~ **2 mV rms**
- Counting rate > **2 Mevts/s** (full chip, full waveform), up to 10 Mevts/s with Region Of Interest (ROI)

Power distribution



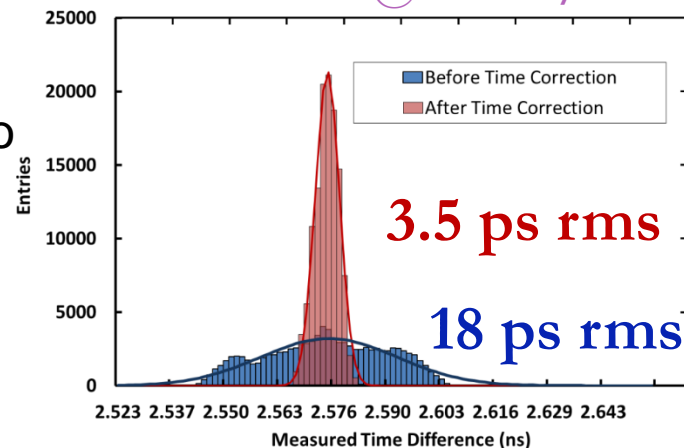
- Wilkinson ADC works with internal **1.3 GHz** clock

- Dynamic range of **1V**
- Gain dispersion between cells ~ **1% rms**
- Non linearity < **1.4 %** peak to peak
- After correction of each cell (linear fit):
noise = **0.95 mV rms**



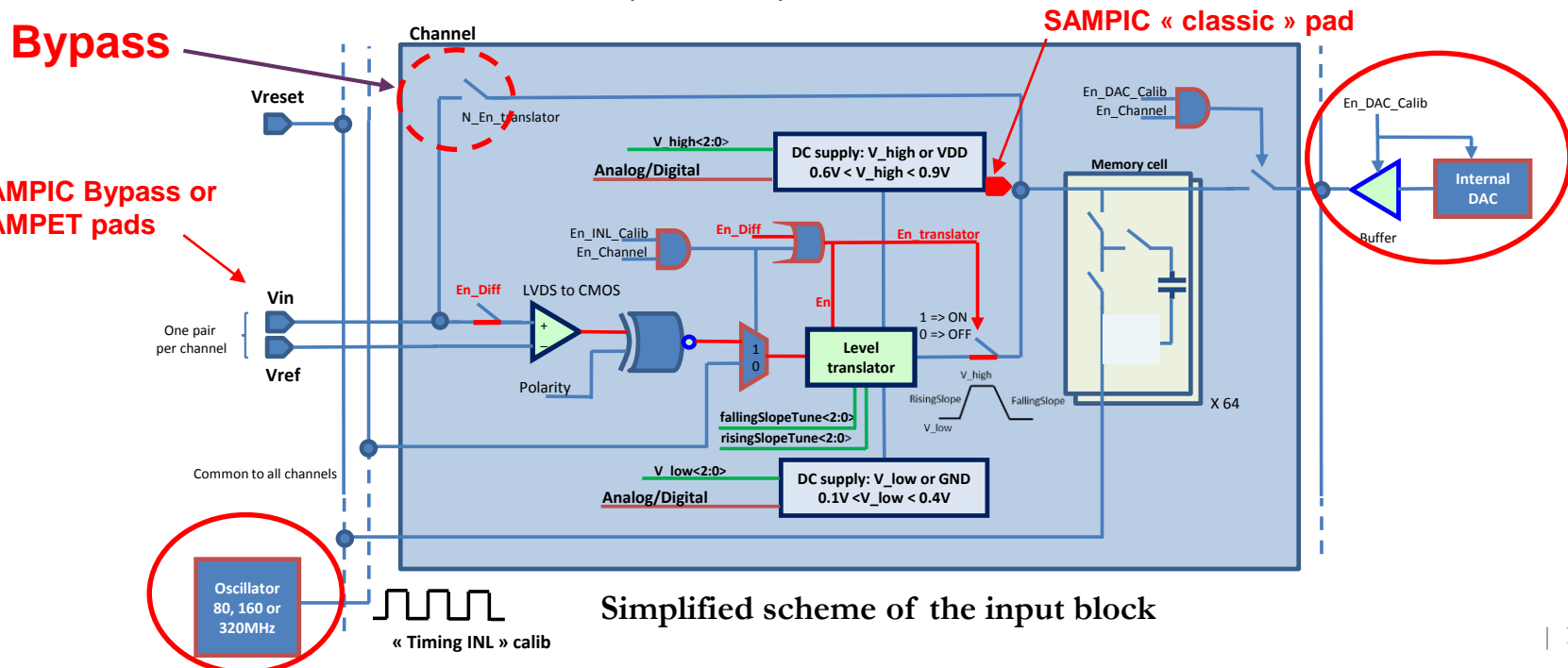
- Time Difference Resolution (TDR):
- Raw non-gaussian sampling time distribution due to DLL non-uniformities (TINL)
- Easily **calibrated & corrected** (with our sinewave crossing segments method [D. Breton&al, TWEPP 2009, p149])

Ex: TDR @ 6.4 GS/s



SAMPIC V3 INPUT BLOCK

- Currently used version of the chip submitted in **May 2017**
- Translator input block :**
 - **Input signal can feed the memory directly (Bypass Mode)** or pass through a **translator** (SAMPET mode: from differential digital to internal levels optimized for SAMPIC → compatible with *SuperNiNo* SLVS output level)
 - It permits among others:
 - **Self calibration of the chip (amplitude & time)**
 - Compatibility with (small amplitude) **digital differential signaling**
- Fixed amplitude** at translator output → we only need to read a **few samples** (ROI) and fast conversion can be used (≤ 8 bits) => **behaves like a TDC**



TIME RESOLUTION: External vs Self Calibration

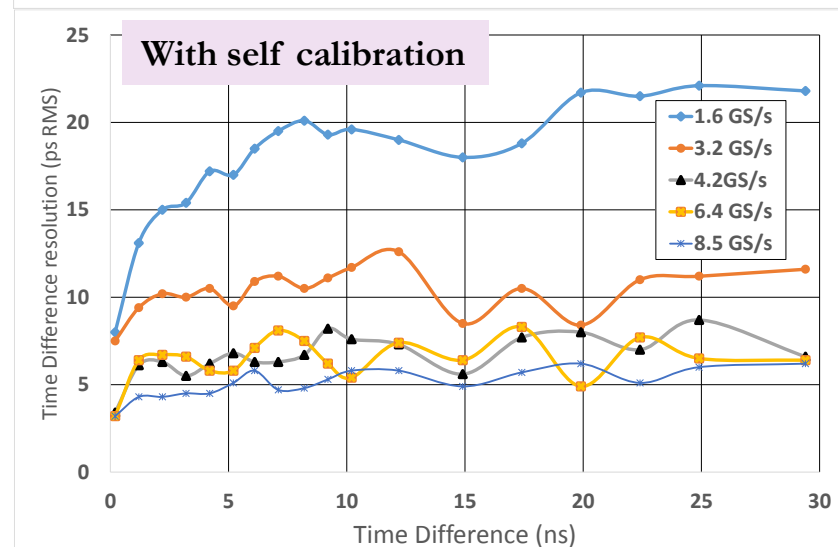
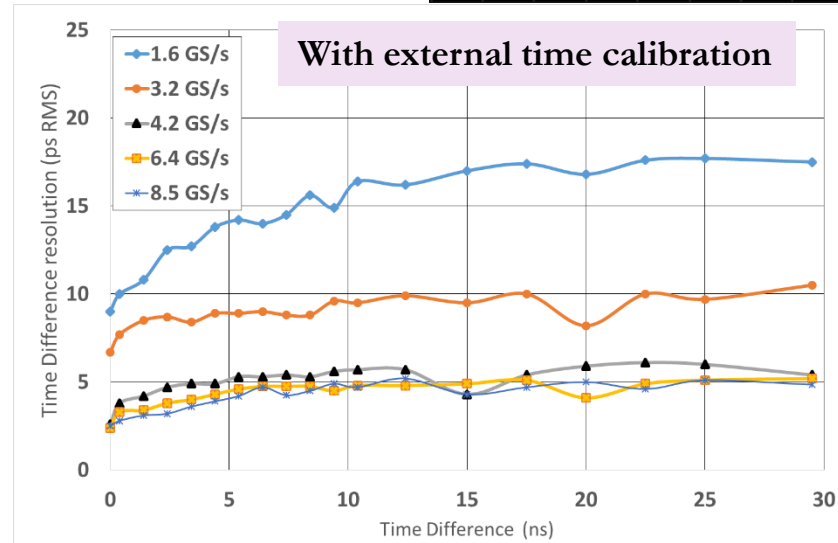
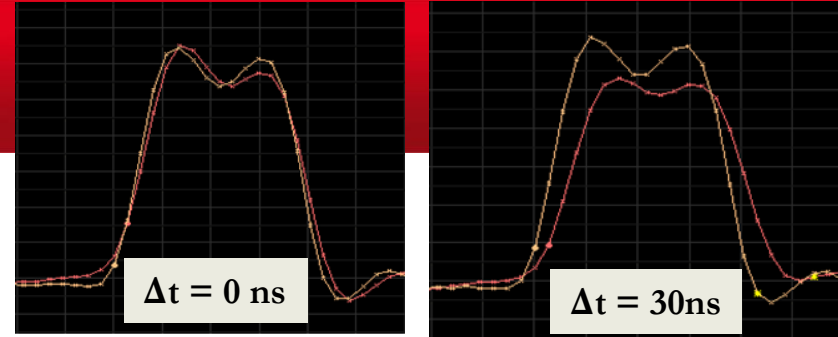
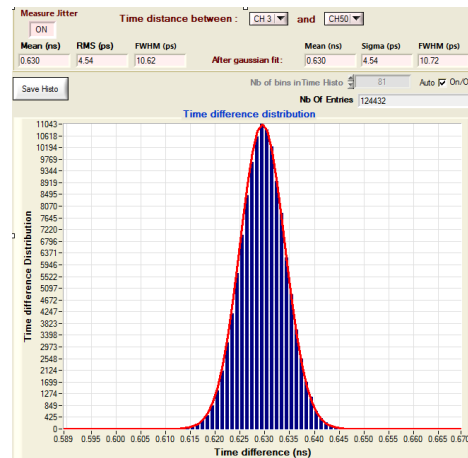
- The new DLL has been re-worked for **improving the resolution for the lower sampling frequencies**
(3 different sizes of starving transistors can be selected in the main DLL in order to optimize its INL and jitter)
- Delays made by a cable box => rise time degrades with delay ...
- With external time-calibration :
 - A TDR of **~5 ps rms** for $4.2 < F_s < 8.5$ GS/s
 - The **TDR < 10 ps rms** for 3.2 GS/s
 - TDR < 18 ps rms** for 1.6 GS/s
- With **self-calibration**
 - Limited jitter degradation (~20%)
 - Permits **full integration in compact detection systems** ...

Between 2 chips:

@ $F_s = 6.4$ GS/s

$\Delta t = 0.63$ ns

=> **TDR = 4.5 ps rms**

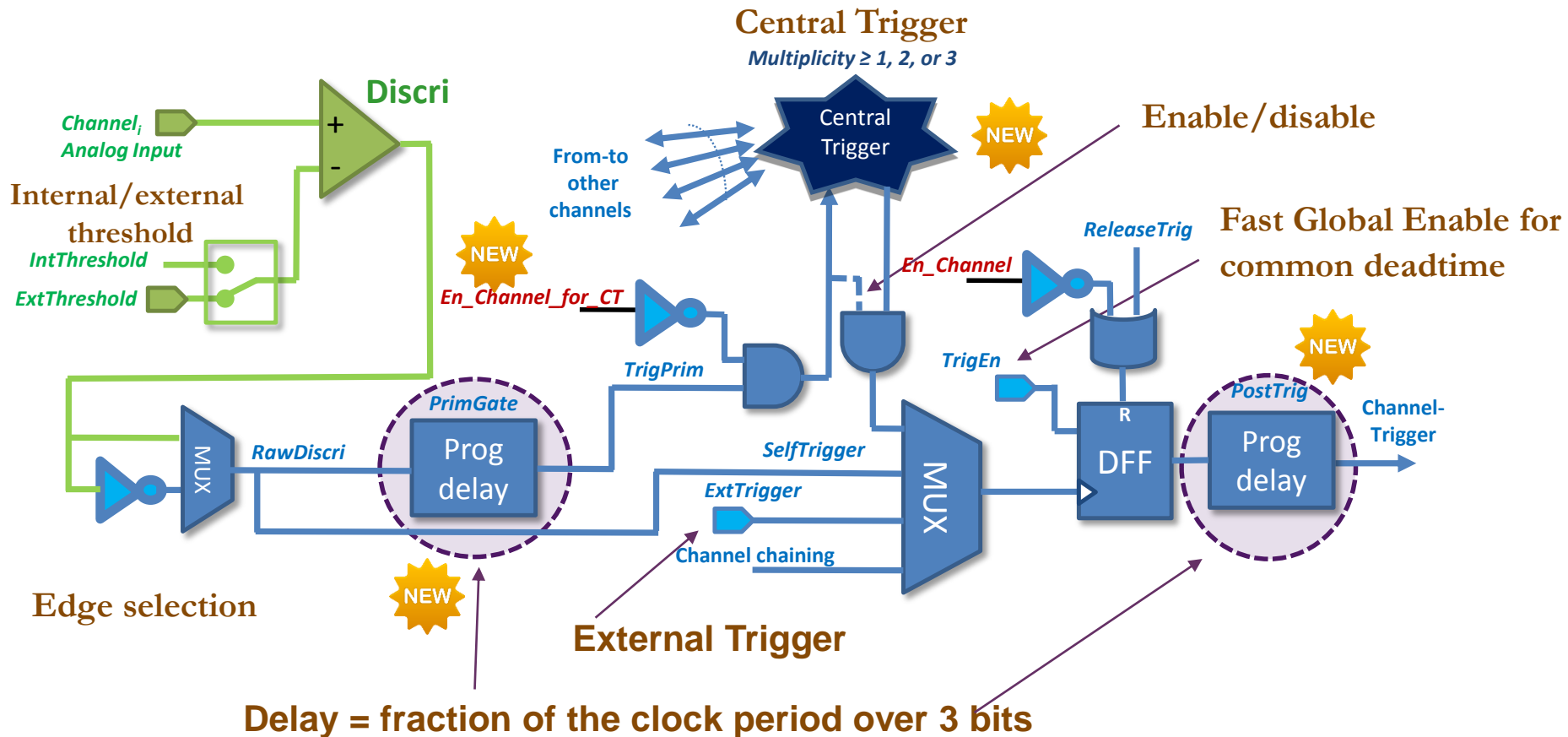


SUMMARY OF MAIN FEATURES OF SAMPIC V3

- Improved “central trigger” (OR, multiplicity of 2 & 3) with possibility of common deadtime or selecting only channels participating in decision
- Improved PostTrig (very useful for low frequencies)
- Channel chaining option: user-defined sets of channels can be chained in time.
- “Ping-Pong” (toggling) mode: channels work in pairs.
- Integrated TOT measurement and trigger filter based on TOT
- All DACs necessary for controlling the chip have been integrated
 - ADC resolution internally selectable between 7 and 11 bits
- Auto-conversion mode for ADC: the conversion can be automatically started when an event is detected, independently for each channel.
 - Reduce the required external digital electronics
 - But the the handshake mode with the FPGA permits building a **2nd Level trigger** based **on many chips** for a common event selection
- Auto-calibration (Time INL): dedicated signal sources are implemented in the chip in order to perform time INL calibrations in standalone.

TRIGGER SCHEME

- One **very low power** signal **discriminator/channel**
- One 10-bit DAC/channel to set the **threshold** (which can also be external)
- Several trigger modes programmable **for each channel**:



Only the triggered channels are in dead time

TRIGGER PANEL IN THE DAQ SOFTWARE

The screenshot shows the 'External Trigger' and 'Advanced Trigger Options' panels. The 'External Trigger' panel has 'External Trigger Type' set to 'External Sig', 'Level' set to 'TTL', and 'Edge' set to 'fL'. The 'Advanced Trigger Options' panel has 'Enable Ping Pong' disabled, 'SAMPIC 1' selected, 'Enable Common DeadTime/Chip' disabled, 'Enable Level 2 Coincidence Mode' checked, and 'Level 2 Primitives Gate' and 'Level 2 Latency Gate' both set to 20 ns. The 'Central Trigger Parameters' panel has 'Central Trigger Type' set to 'Triggered CHs >= 2', 'Central Trigger Effect' set to 'Only if participating to CT', 'Primitive Source' set to 'Gated Discri', and 'Channels Primitives Gate Length' set to 0. The 'Central Trigger Channel Sources' section shows a grid of checkboxes for channels Ch00 through Ch15, with 'All channels' selected.

External Trigger

External Trigger Type: ☐ Software ☐ Internal Osc ☒ External Sig

Level: TTL ☒ NIM ☐ Edge: ☒ fL ☐ fH

Use Ext Trig as Enable Trig ☐ Open Gate on Ext Trig ☐ Ext Trig Gate: 0 ns

Advanced Trigger Options

Enable Ping Pong ☐ SAMPIC 1

Enable Common DeadTime/Chip ☐ (recommended for Central Trigger Mode)

Enable Level 2 Coincidence Mode ☒

Select Logic option between ASICs: Global AND ☐ (0 OR 1 OR 2) AND 3

Level 2 Primitives Gate: 20 ns (Ch ToConv)

Level 2 Latency Gate: 20 ns

Channel Trigger Mode

☒ Self Trigger ☐ External Trigger ☐ Central Trigger ☐ Chained to previous Channel

Internal Threshold (relative to Baseline): 0.600 1.000 0.400 1.400 0.200 1.600 0.000 1.800 0.000 Edge: ☒ fL ☐ fH

Central Trigger Parameters: ALL SAMPICs

Central Trigger Type: ☐ Central OR ☒ Triggered CHs >= 2 ☐ Triggered CHs >= 3

Central Trigger Effect: ☒ Only if participating to CT ☐ Trig All Channels

Primitive Source: Raw Discri ☐ Gated Discri ☒

Channels Primitives Gate Length: 0 x 1/8 Clk Period = 00 ns

Central Trigger Channel Sources: All channels: ☒ Off On Ind

Ch00 ☐ Ch01 ☐ Ch02 ☐ Ch03 ☐ Ch04 ☐ Ch05 ☐ Ch06 ☐ Ch07 ☐
Ch08 ☐ Ch09 ☐ Ch10 ☐ Ch11 ☐ Ch12 ☐ Ch13 ☐ Ch14 ☐ Ch15 ☐

Individual channel trigger modes

Advanced PingPong Mode

2nd Level Coincidence Mode: (Two options available)

Coincidence Gate

Central Trigger

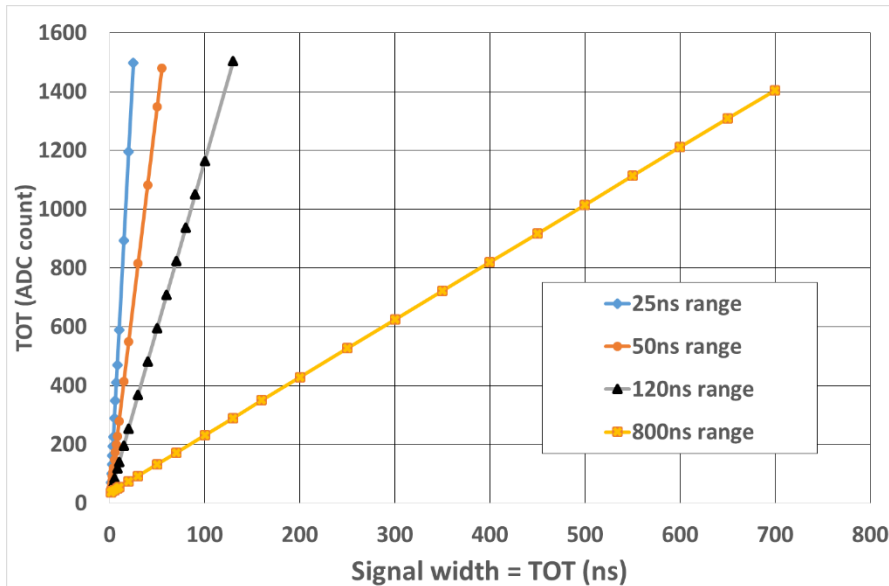
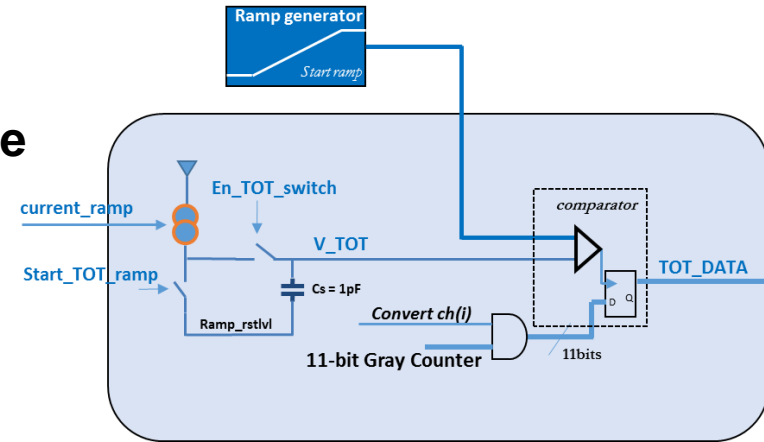
Multiplicity

converting channels only if participating to Central Trigger

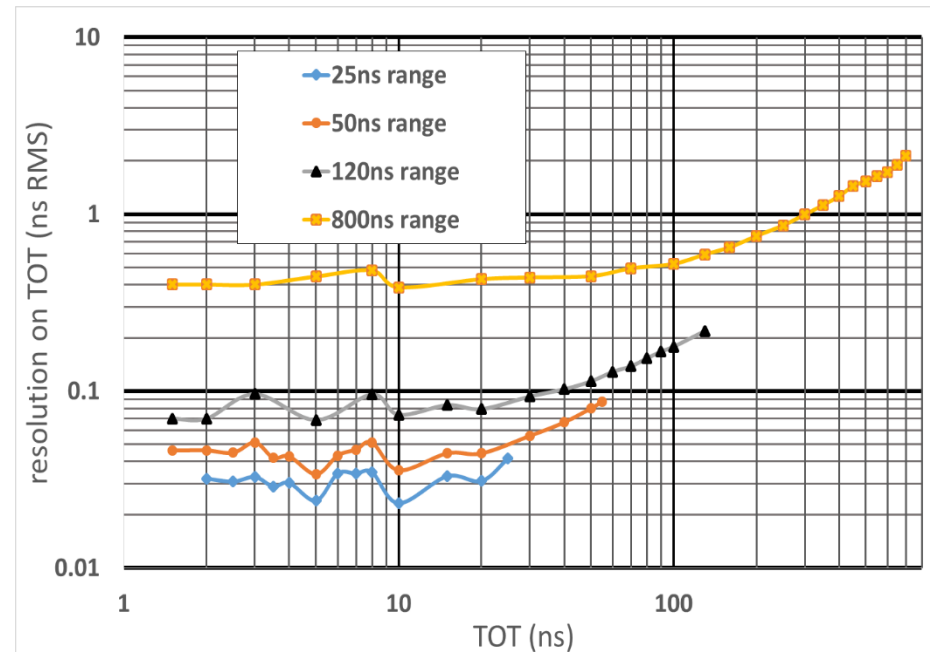
Select channel that participate to Central Trigger

TOT MEASUREMENT

- SAMPIC is designed to digitize a short signal or only a small part of a longer one (eg rising edge) to extract the timing → then **the other edge** is missed
- Addition of a **ramp-based Time to Amplitude Converter** for each channel seen as a 65th memory cell during digitization → ~10bit TOT TDC



Measurement ranges between 2 and 700 ns.



TAKING DATA WITH DETECTORS

- SAMPIC modules are already used with different detectors on **test benches or test beams**. A lot of examples were presented at the **WaveCatcher and SAMPIC workshop** the 7th and 8th of February 2018 in Orsay.
- Tested with **PMTs, MCPPMTs, APDs, SiPMs, fast Silicon Detectors, Diamonds**: performances are equivalent to those with high-end oscilloscopes
 - Different R&Ds ongoing with the **TOF-PET** community (CERN, IRFU,...)
 - SAMPIC has been used for test beams of **TOTEM at CERN**
 - It was also used for **fast mesh-APD** characterization and test beams
 - **TOTEM** has developed a CMS-compatible motherboard housing SAMPIC mezzanines which has been installed on the LHC
 - SAMPIC is used for test beams of **SHIP** collaboration. It is now considered as baseline readout option for the **Fast Timing Detector**, the **Surround Background Tagger** and the **Muon Detector**.
 - Envisaged for **T2K Upgrade**: 256-channel **Timing Detector**.

ON-CHIP TOT FILTER

Initial request for SAMPET & funding by
C. Williams (CERN+INFN)
& K. Doroud (CERN)

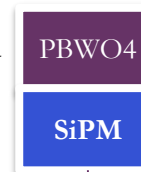
© S. Sharryy



^{22}Na
(511keV)

3x3x5 mm3
200 Ph/MeV

3x3mm²
20°C



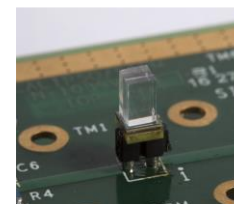
Only few photons

Noisy

Ampli
40dB



SAMPIC



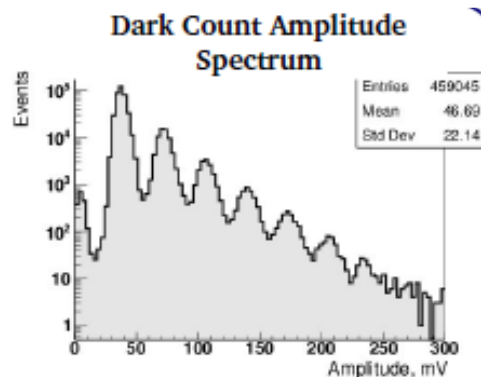
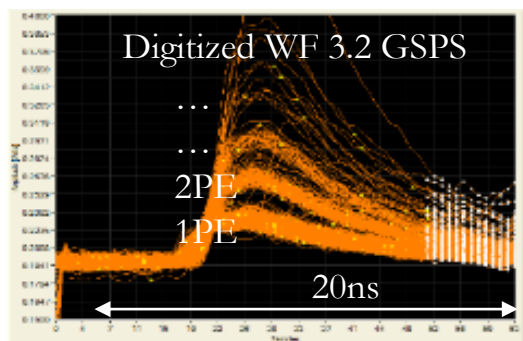
SiPM: KETEK PM3350TP-SB0
3x3 mm², 50μm pitch, trench design,
Operation @ 29V (2.5V overvoltage)

Goal: demonstrate the noise rejection capability using the TOT filter which rejects events with TOT < programmable limit

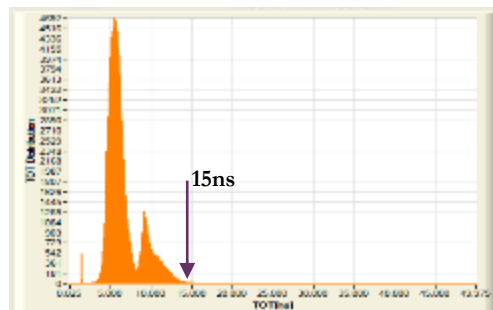
SiPM coupled to crystals (here KETEK SiPM + PbWO₄ + ^{22}Na Source,
@ 20°C => 1PE ~ 40mV

Th = 20 mV (0.5 PE), TOT_Filter OFF:

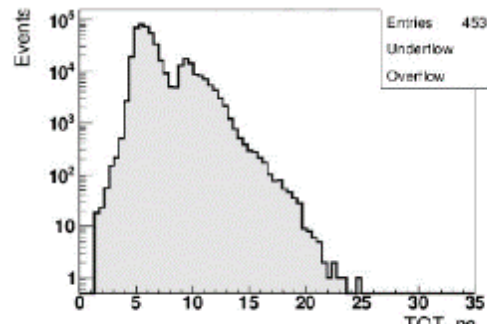
=> 700 kHz rate of events / 4.5 MHz raw rate (dark count)



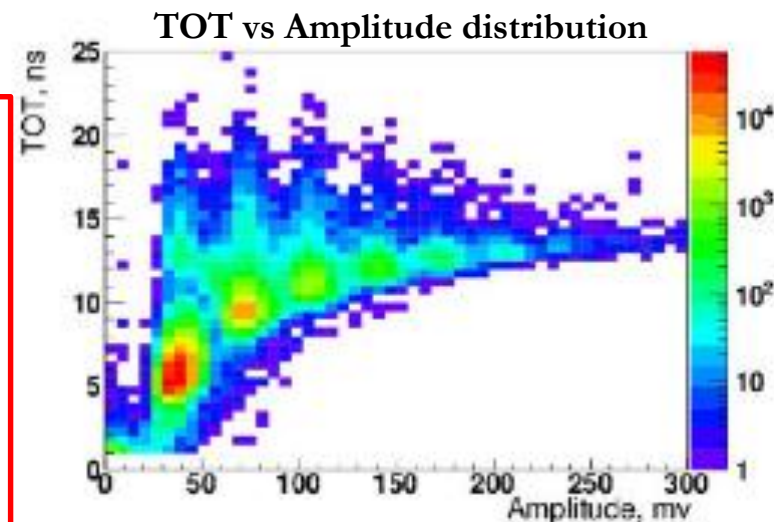
TOT spectrum (digitized by the chip)



Lin scale



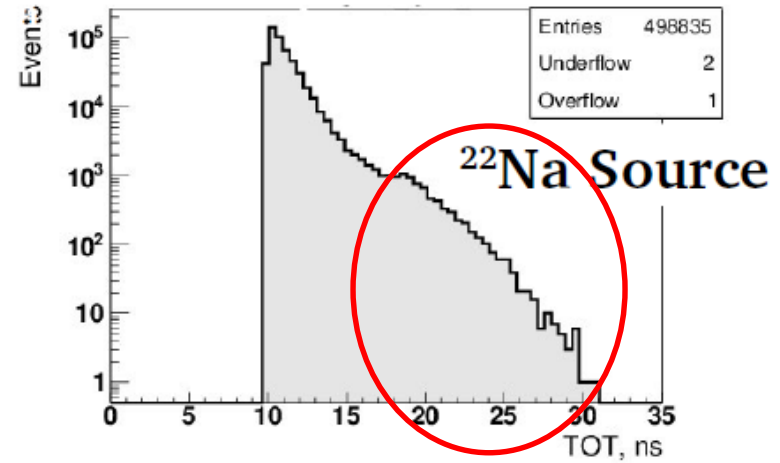
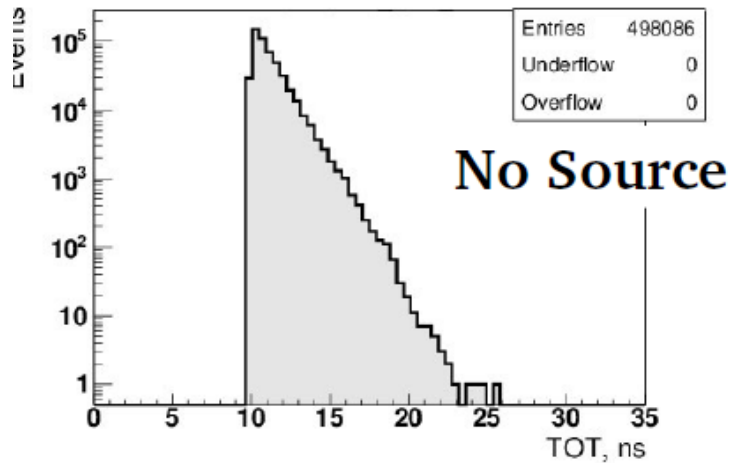
Log Scale



NEW IN SAMPIC V3 : ON-CHIP TOT FILTER => NOISE FILTERING

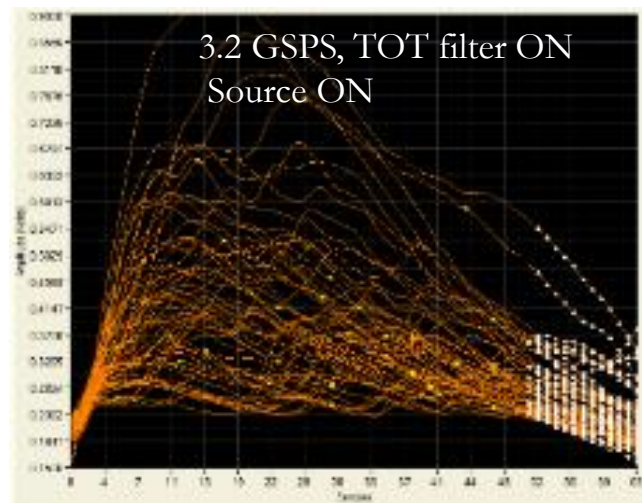
© S. Sharyy

Threshold : 50 mV (1.25 PE), TOT filter = 10ns



TOT spectrum without source
(60kHz if TOT filter OFF)
60 Hz if TOT filter ON

TOT spectrum with source
(60kHz if TOT filter OFF)
200Hz TOT filter ON

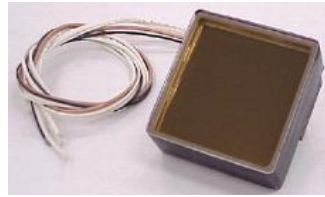
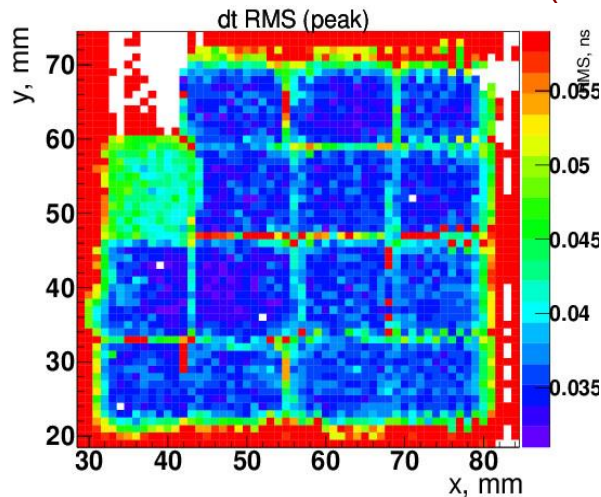


=> 140 Hz from source!

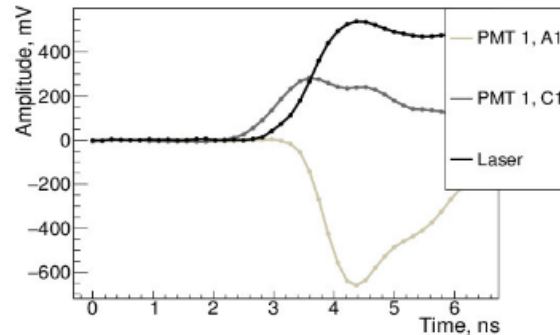
99.9% of the noise is rejected

SCAN TEST OF MCP-PMT © S. Sharyy

PMT resolution for anodes (ns rms)



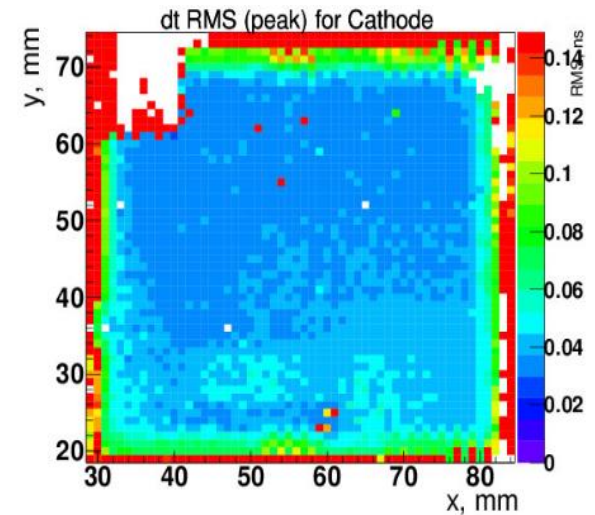
PLANACON XP85012 used for CALIPSO/PECHE: 64 channels grouped by 4.



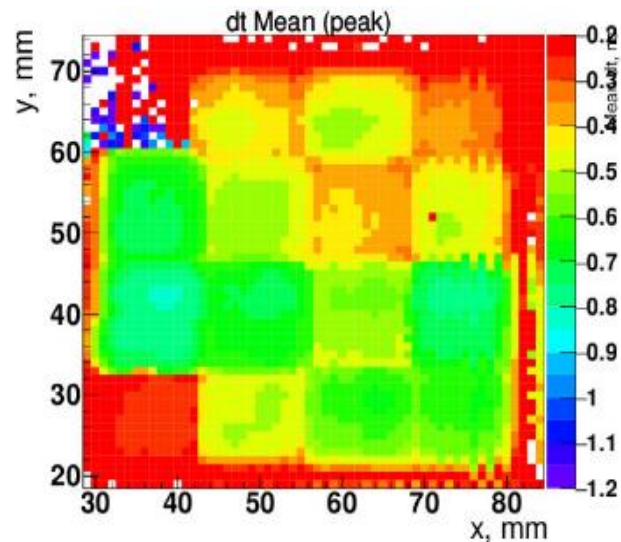
- We measure time difference between Laser and Signals.
- Step of 1mm, 2 sec / per stage, 0.5 sec / move
- SAMPIC in two-level trigger coincidence mode (anode & laser)
- Data taking rate: 50 kHz

**Total Scanning Time :
2 hours!**

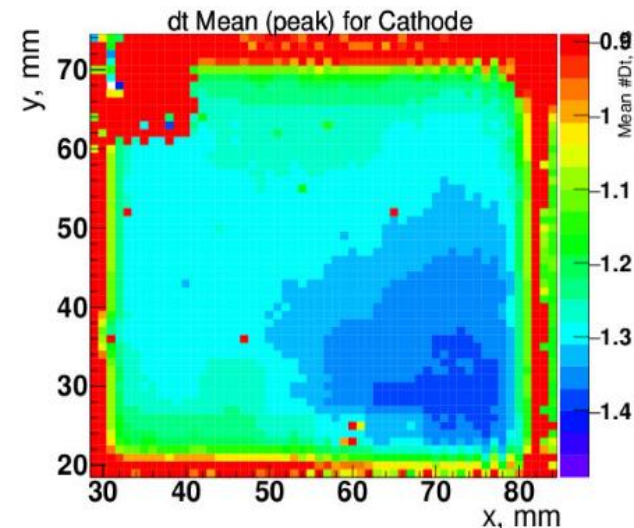
PMT resolution for cathode (ns rms)



PMT delay for anodes (ns)



PMT delay for cathode (ns)



OTHER SPECIAL FEATURE

- **External Trigger Input:**

- This input can sample a counter running synchronously with the **SAMPIC clock : 40- bits timestamp.**
- Each trigger input is also associated to a **Trigger ID (24 bits)**
- In order to be able to synchronize multiple sub-systems in testbeams, a 16 bit-Trigger ID can also be decoded from a **serial stream** (RS232 like) on the Trigger Input. It has been used by TOTEM in test beam this summer with a fast TPC.
- Multipurpose I/O connector : (example : SPI for MUSIC boards (Barcelona))



External TrigIn

TIMING DETECTOR PROTOTYPE FOR SHIP

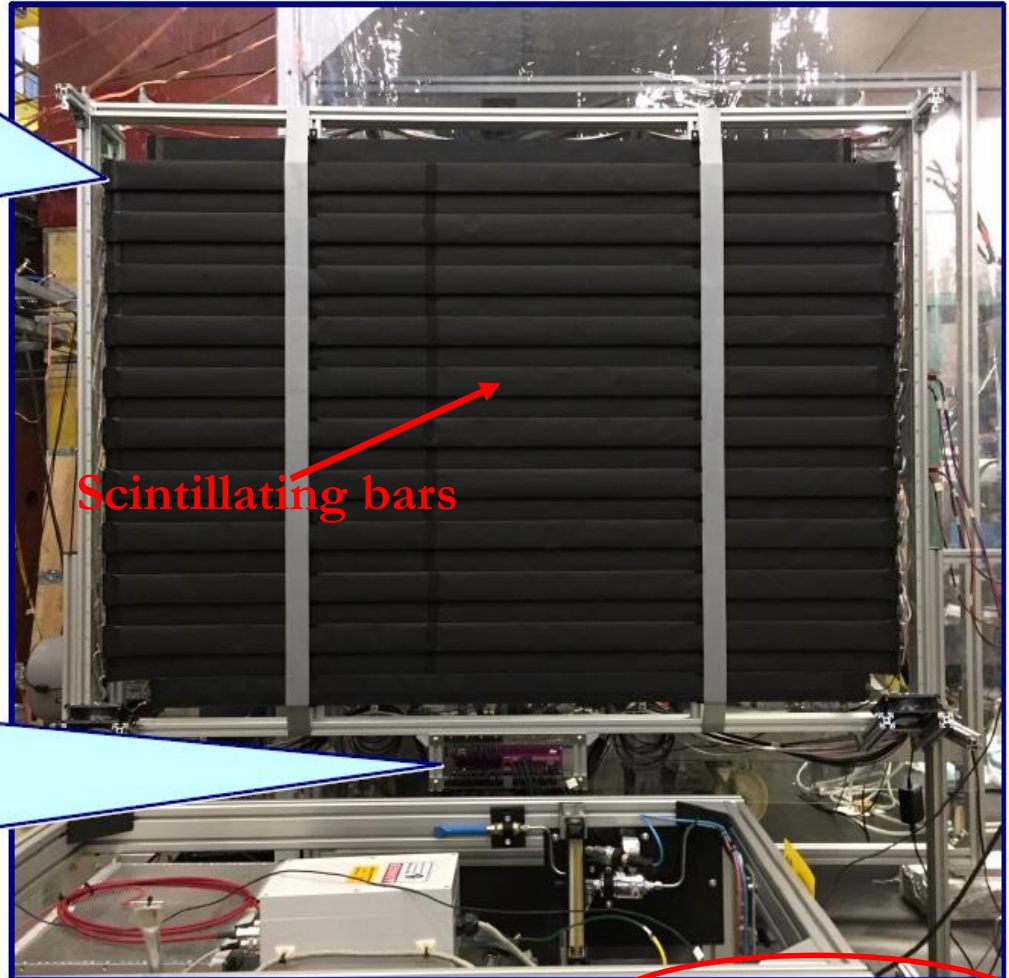
(© A.KORZENEV)

Testbeam Aug 15 – Sep 19, East hall T10 of CERN PS

Readout by SiPM-arrays



Mini-Music Board
(see Poster ...)



Scintillating bars

64ch SAMPIC module



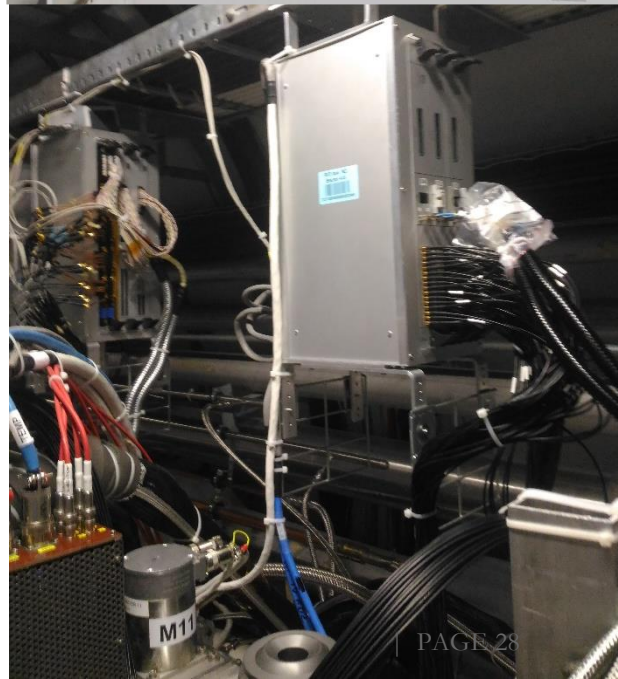
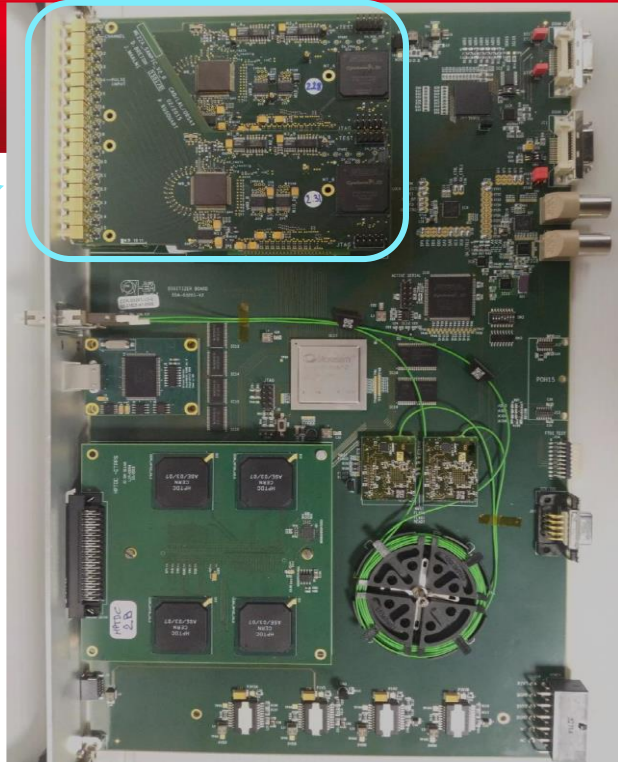
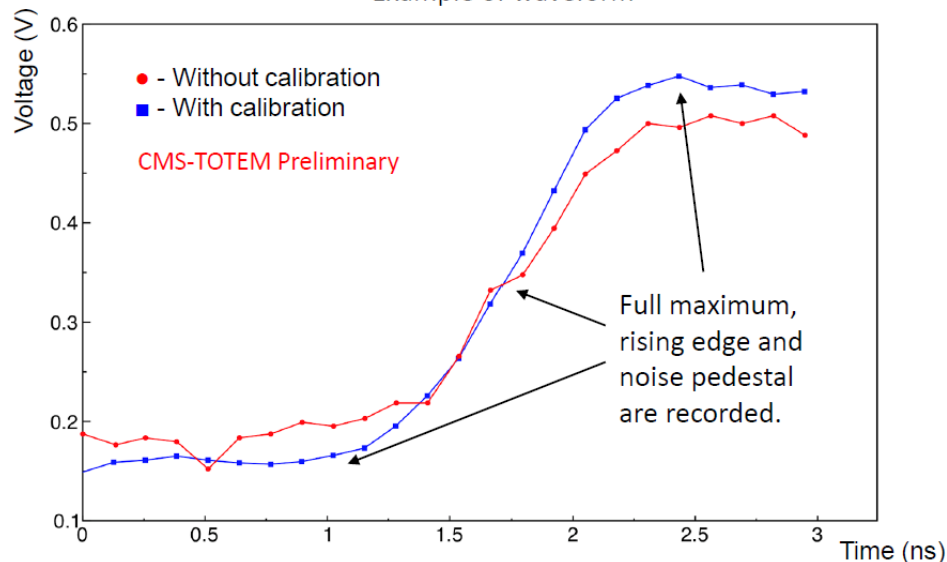
Bar length 1.7m, 2 side readout, 80 ps time resolution
arXiv:1709.08972

PROTOM TIMING SYSTEM OF TOTEM

(© E.BOSSINI)

- 192 channels of **SAMPIC mezzanines** were mounted on motherboards especially designed by the **TOTEM** team, also housing HPTDCs
- This permitted interfacing an almost standard SAMPIC firmware with the environment of the **CMS Trigger and DAQ**
- **Sampling frequency** was set to **7.8 GS/s** and ADC conversion to **8 bits**
- Waveform length was set to **24 samples**
- Hit rate per channel was close to **1 MHz**
- Calibration corrections were applied **offline**

Example of waveform



CONCLUSION



- SAMPIC is a full **System On Chip**:
 - Analog or digital input, fully digital output
 - All the DACs and calibration generators are integrated
 - It just requires power, clock, and a simple interface with an FPGA
 - **Small power consumption ~10 mW/channel**
 - All the channels can be fully independent
 - Raw counting rate can go **>> 100 kHz/ch.**
 - Large choice of smart triggers
- It can be used for a **highly integrated tiny module** (cm³) as well as for **large scale detectors** (nuclear or high energy physics, TOF-PETs, ...).
- Different types of **modules** have been developed: **16 to 256-channel modules**.
- On going licensing with **CAEN**.
- **End of AMS 0,18 μm** => chip production ongoing and possible migration to another technology (but original IBM 0.18μm should now be accessible)
- For more information:

<http://wpsist.lal.in2p3.fr/wasiw2018/>



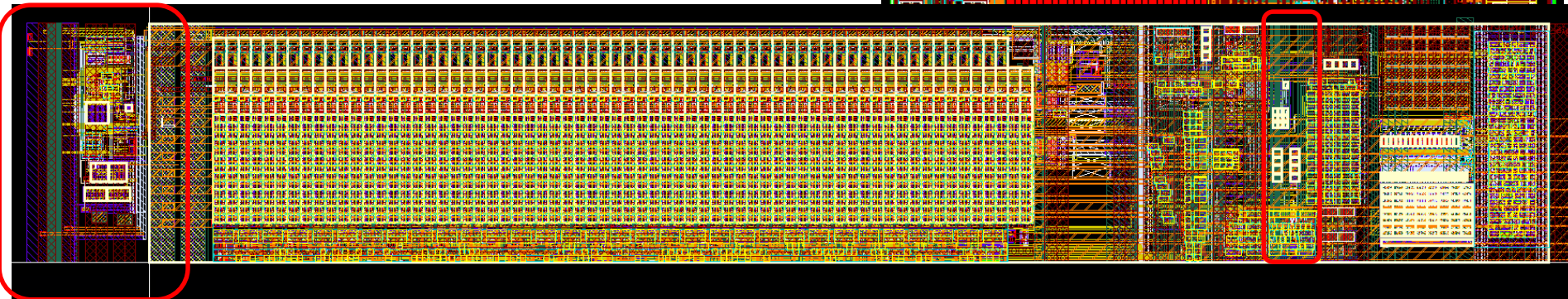
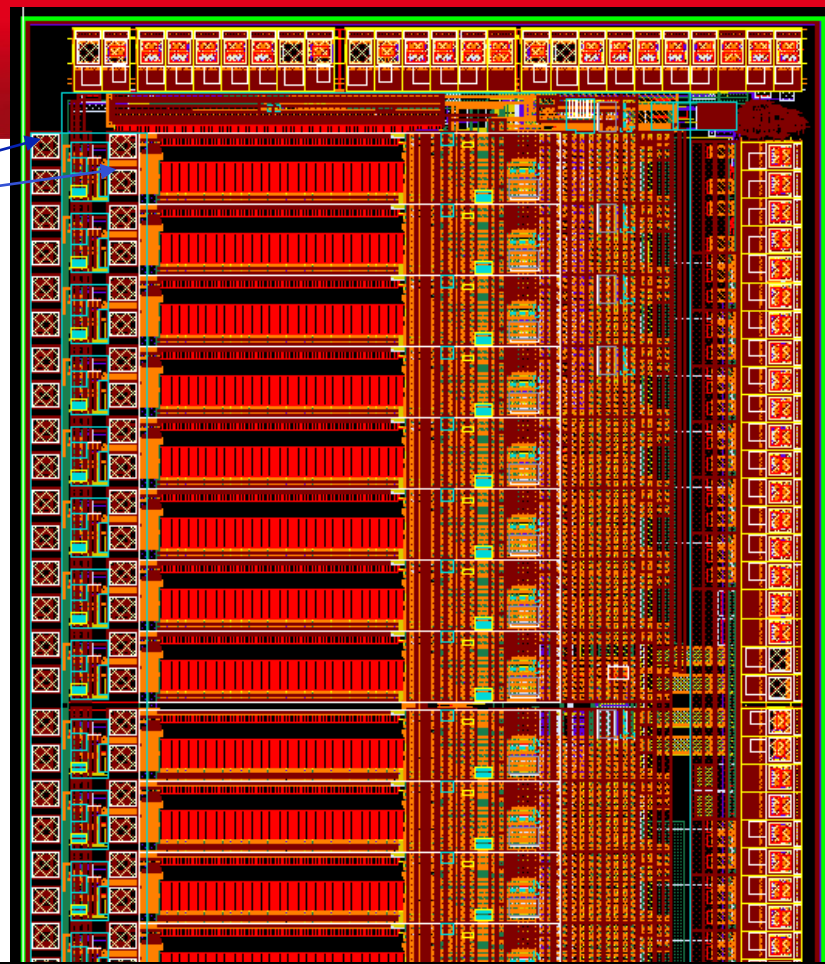
SAMPIC: PERFORMANCE SUMMARY

		Unit
Technology	AMS CMOS 0.18 μ m	
Number of channels	16	
Power consumption (max)	180 (1.8V supply)	mW
Discriminator noise	2	mV rms
SCA depth	64	Cells
Sampling speed	0.8 to 8.5 (10.2 for 8 channels only)	GSPS
Bandwidth	> 1	GHz
Range (unipolar)	~ 1	V
ADC resolution	7 to 11 (trade-off time/resolution)	bits
SCA noise	< 1	mV rms
Dynamic range	> 10	bits rms
Conversion time	0.1 (7 bits) to 1.6 (11 bits)	μ s
Readout time / ch @ 2 Gbit/s (full waveform)	< 450	ns
Single Pulse Time precision before correction (4.2 to 8.5 GS/s)	< 15	ps rms
Single Pulse Time precision after time INL correction (4.2 to 8.5 GS/s)	< 3.5	ps rms

BACKUP SLIDES

SAMPIC_V3 LAYOUT

- **Double row of input pads:**
 - External row: standard cabling for usual applications where translator stage can be used and self calibration performed
 - Internal row: for optimal bandwidth, time precision and testability
- No more NC pins.

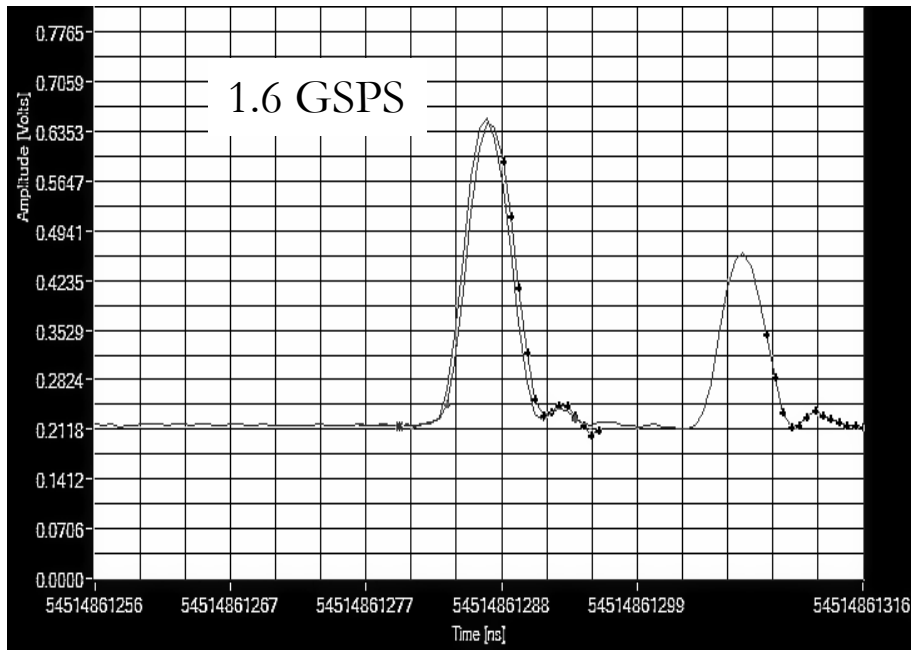


- Dimensions of a channel: $200\mu\text{m} \times 1.3\text{mm}$

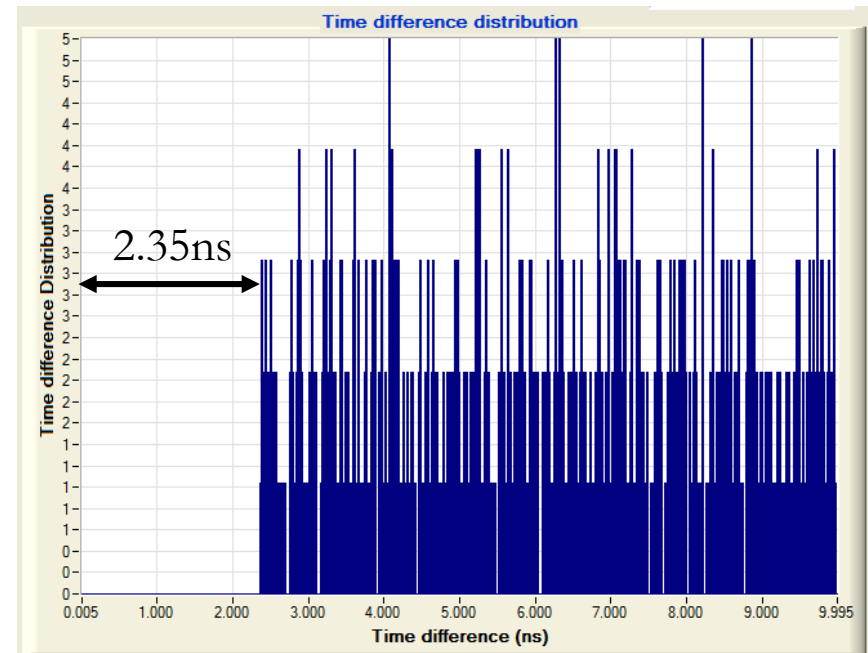


PING-PONG MODE

- **PING-PONG**: use alternatively 2 SAMPIC channels, **connected or not to the same source**, to reduce the dead time and allow double or conditionnal pulse detection.
- **Min re-triggering distance** : **2.35 ns** (see below)
- Drawback: number of channels divided by a factor 2 if source is common



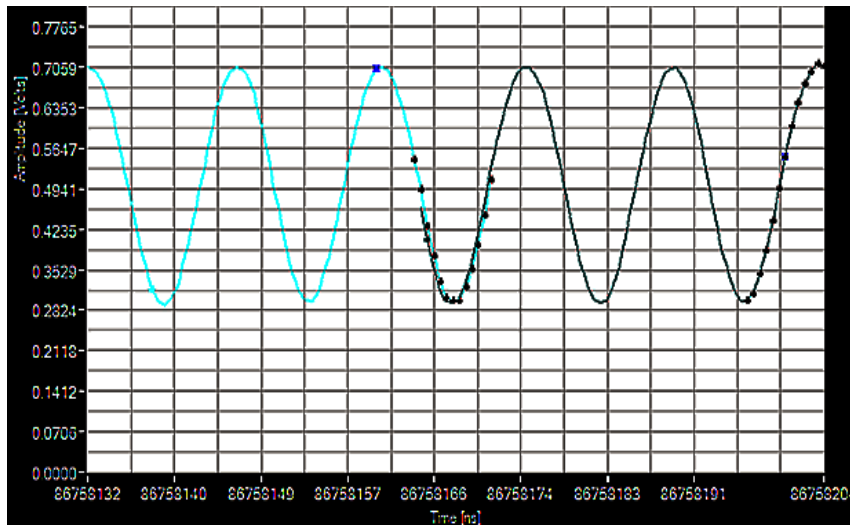
1st pulse recorded on channel 2
2nd pulse recorded on channel 3



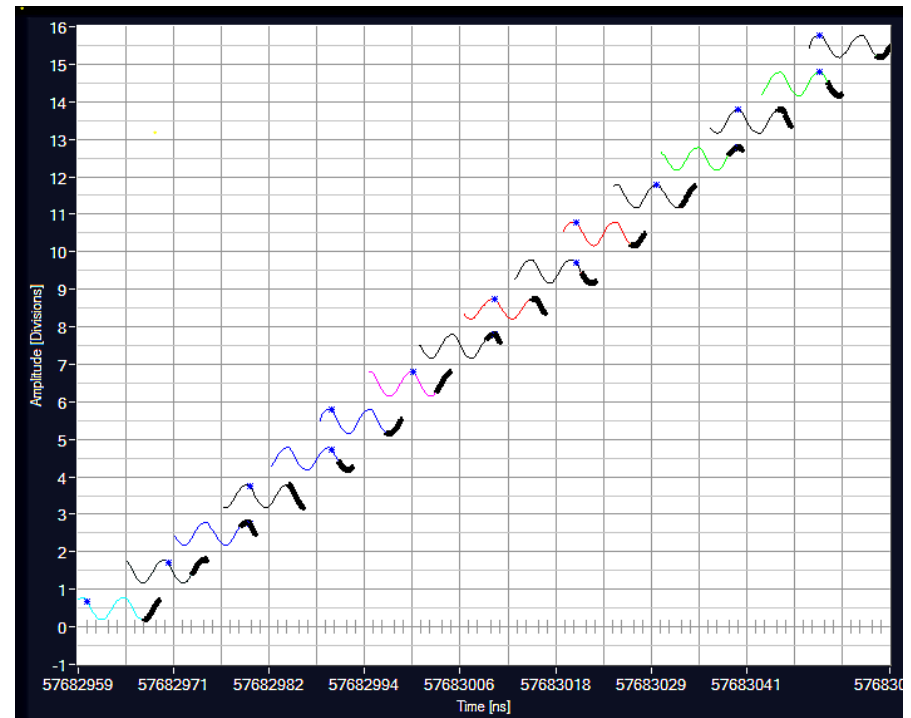
DeadTime (measured with 2 random pulses)
=> Time difference distribution

CHAINED MODE

- **Goal:** extend the **depth** of SAMPIC by **chaining channels** connected to the same source or force triggering of successive channels
- Each channel can be defined as a **Master** that can successively trigger N (1 to 15) other « **Slave** » channels.
- Tens of possible configurations
- The **delay between the channels** is defined by the **POSTTRIG**



2 channels chained @1.6GSPS



16 channels chained @6.4GSPS

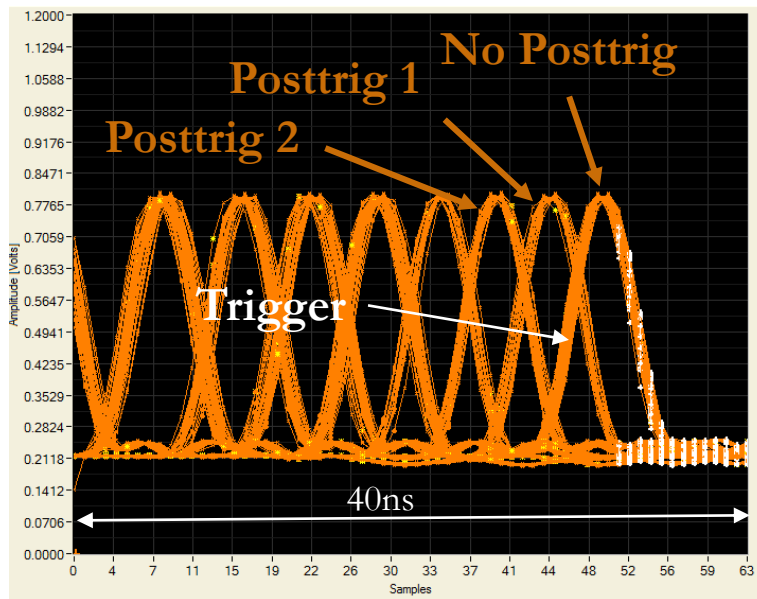
PROGRAMMABLE POSTTRIG

- Allows to “move the signal” by fractions of the acquisition window

=> **oscilloscope-like PostTrig**

- 8-step (~linear) programmable asynchronous delay that must be proportionnal to the sampling frequency

- Mostly useful for low sampling frequencies



Effect of the 8 posttrig values (1.6 GSPS)

SAMPLING [GS/s]

3.2 4.252 6.4 8.512 10.24 1.6 2.133

Low Ext Clk High Ext Clk

0.00 ps/sample

ALL SAMPICs ▼

POST-TRIGGER ☐ On/Off

"Tour de Piste" DELAY

3 4 5 6 7 2 1 0

x 1/8 Clk Period = 0 ns

x 1/8 Clk Period = 0 ns

Recording depth: Shortened ☒ Full

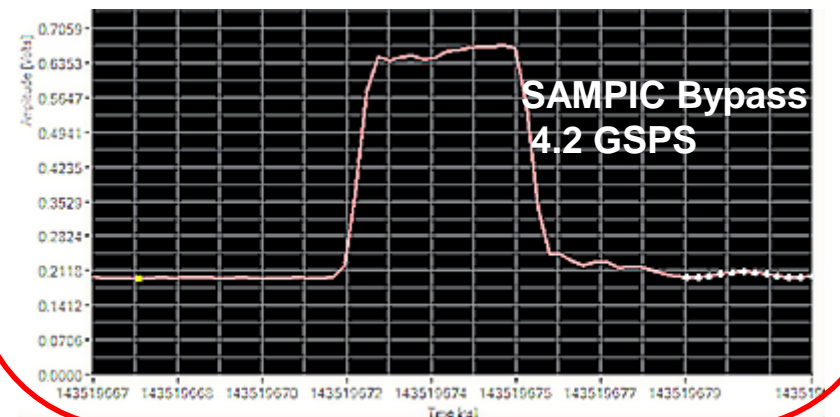
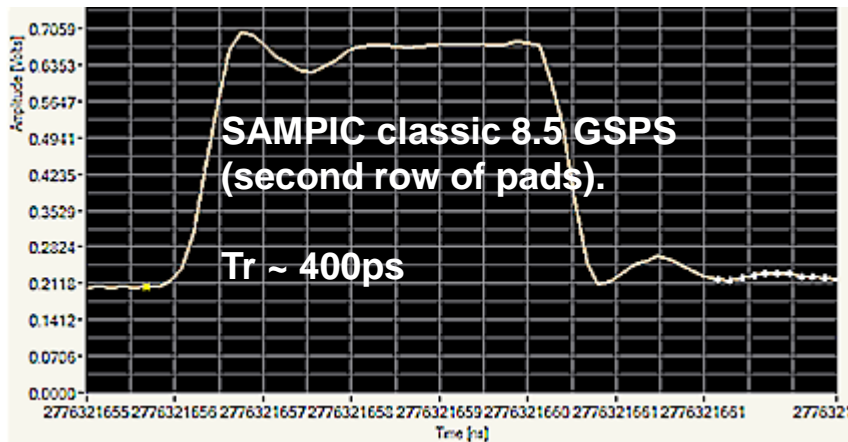
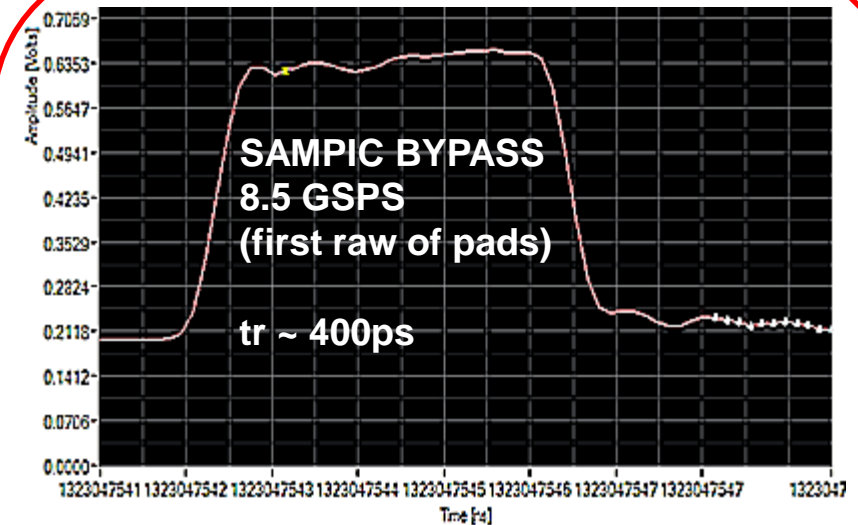
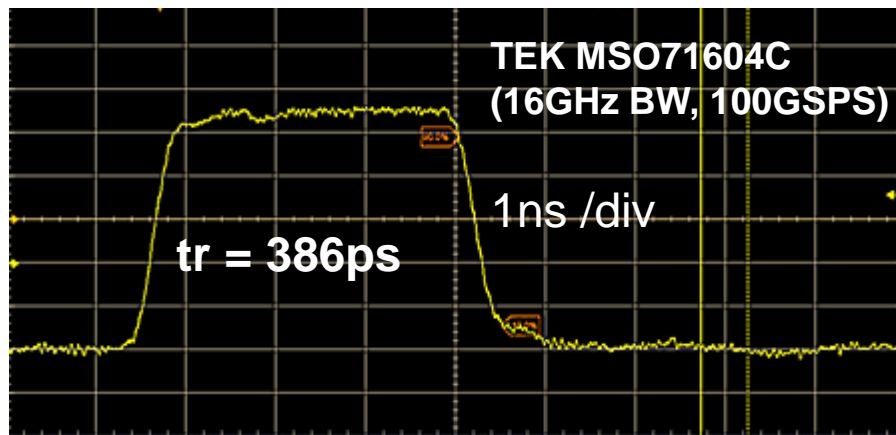
Specified depth: 64 samples

Offset for start of read: 0 samples

Start Read from Trigger Cell + Offset OFF ☒ ON

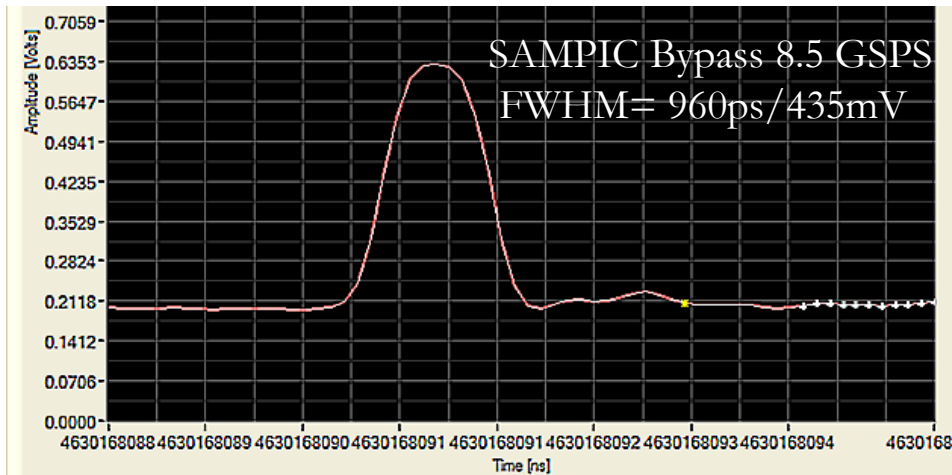
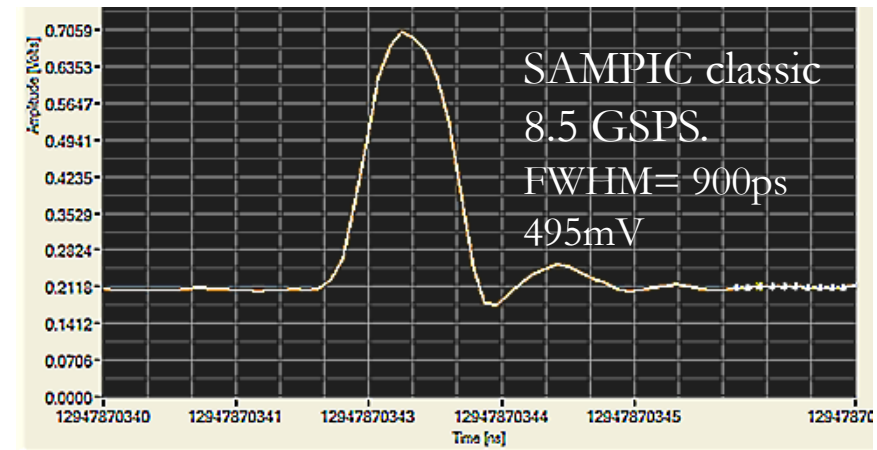
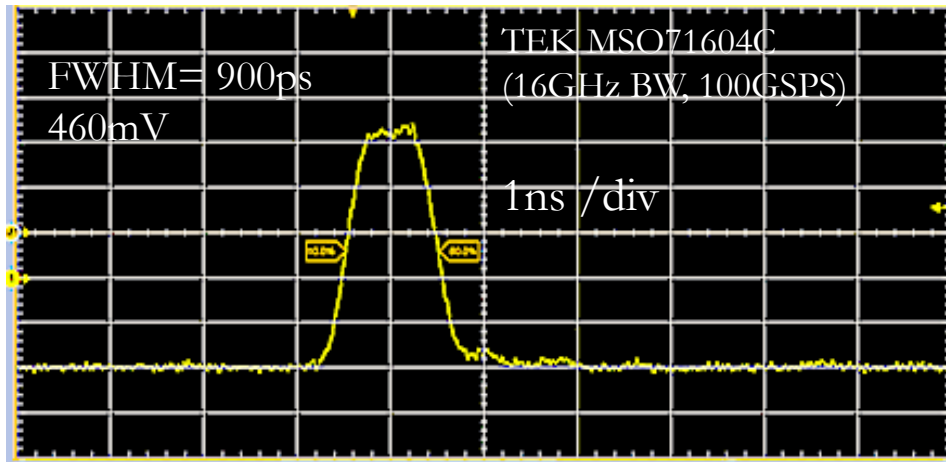
WAVEFORM RESPONSE WITH NEW INPUT CONFIGURATION

- Pulse (~460 mV pp) with sharp edges => compare the response from SAMPIC and from a 16 GSPS oscilloscope:
 - Signal produced by a LeCroy 9214 generator.
 - Permits estimating **SAMPIC bypass bandwidth: > 1 GHz**



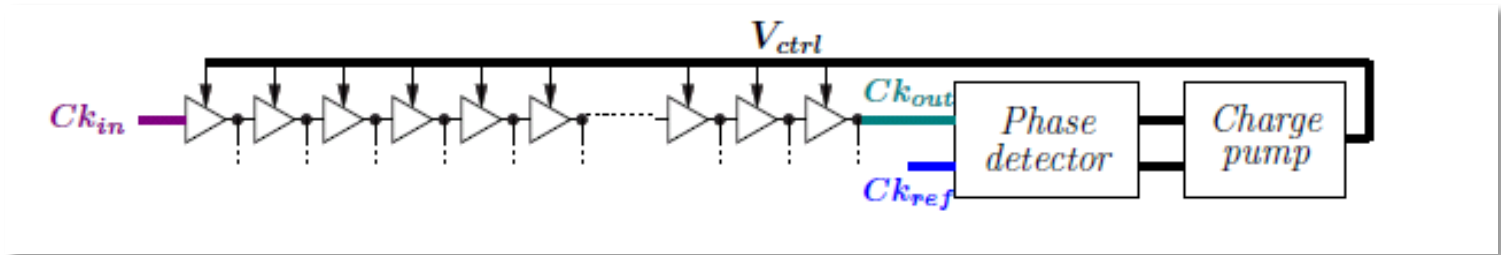
SHORT SIGNAL RESPONSE

Lecroy 9214 signal with 900 ps width



TIMEBASE : VIRTUAL CLOCK MULTIPLICATION BY 64

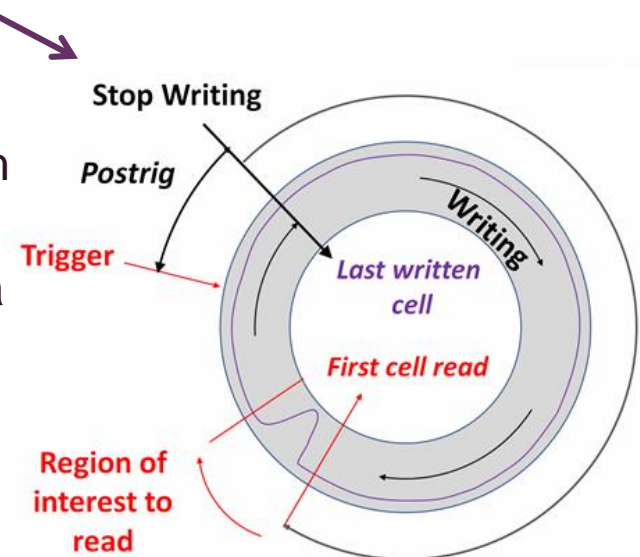
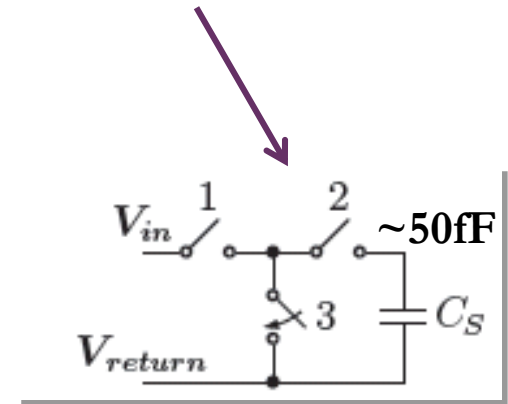
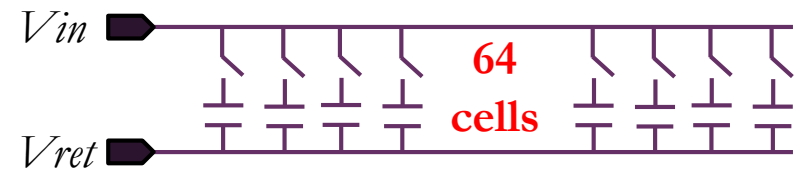
- **One single** 64-step Delay Line Loop. 64 = tradeoff depth/(noise + speed)
- On chip servo-control to the timestamp counter clock
- Provides 64 incrementally **delayed** pulses with **constant width** used to drive the T/H switches of the **64 cells** for **each SCA channel**
- **'virtual multiplication'** by 64 of the TS Clock (100MHz =>6.4GHz)



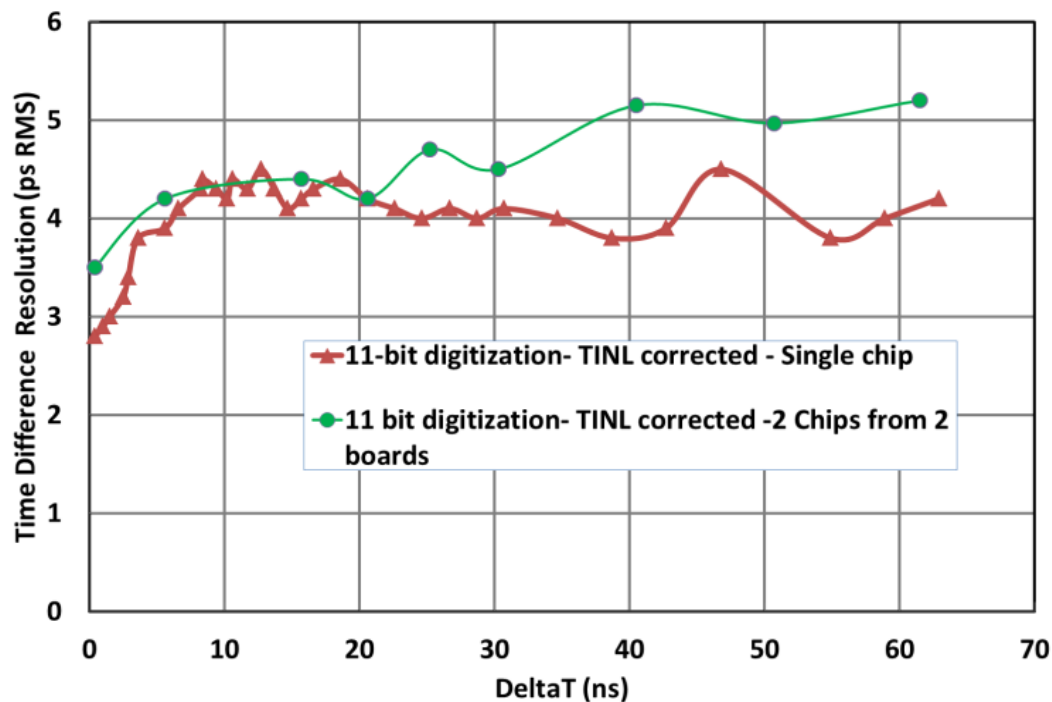
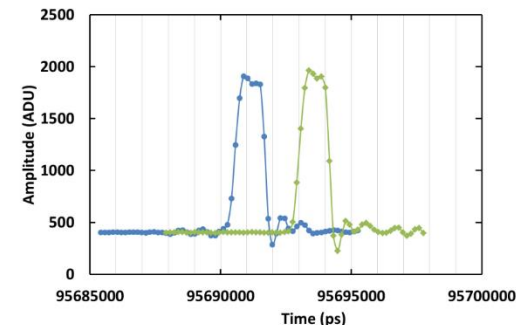
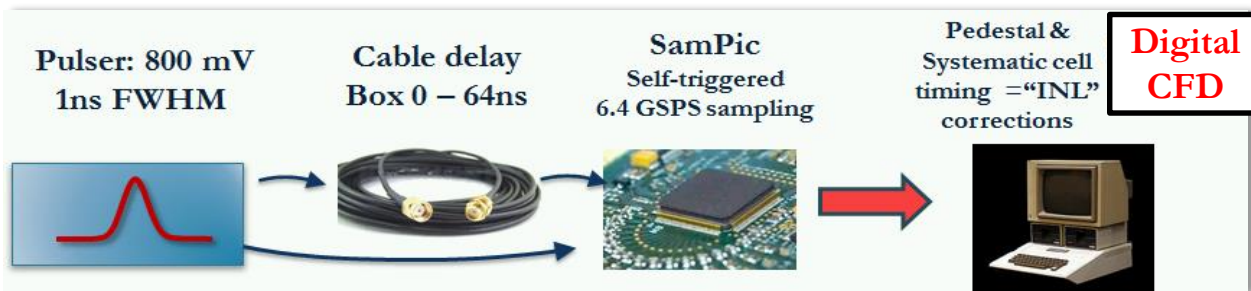
- Each controllable delay is the cascade of 2 starved inverters (inverters with slowed-down edges)
- Drawbacks:
 - Non uniform delays along the DLL → skew that can be calibrated
 - For low sampling frequency:
 - Very slow edges (=> skew + jitter)
 - Limited locking range

ANALOG MEMORY (SCA) IN EACH CHANNEL

- **64-cell deep, No input buffer, single ended**
- Small capacitor + simple switches
- **~ 1 V usable range, > 1.5 GHz BW**
- **Waveform continuously recorded** (circular buffer), then **stopped** on trigger (which also catches the state of the coarse counter)
- **Trigger position marked on DLL cells => medium precision timing** and used for Optional **Region of Interest Readout** (only few samples read)
- Conversion by a Wilkinson (ramp) 11 bit ADC for each cell (clocked @1.25GHz)
 - ➔ compact and high speed for high precision: a cell/cell transfer function) calibration is required
- 1.6 μ s conversion time that can be decreased if lower precision is required.



ΔT RESOLUTION VS DELAY



- TDR < 5 ps rms after time correction.
 - TDR is constant for $\Delta t > 10$ ns
 - ~ unchanged when using 2 chips from 2 mezzanines (slope here comes from slower risetime of 800ps)
 => measurement are uncorrelated
 => channel single pulse timing resolution is < 3.5 ps rms ($5 \text{ ps} / \sqrt{2}$)
- From these 2 types of measurements, we could extract the jitter from the motherboard clock source: ~ 2.2 ps rms
 => SAMPIC's own jitter < 2.5 ps rms

TIMING RESOLUTION (DIGITAL CFD) VS ADC NUMBER OF BITS

- ADC conversion can be sped up (by decreasing the resolution): factor 2 for 10 bits (800 ns), 4 for 9 bits (400 ns), 8 for 8 bits (200 ns), 16 for 7 bits (100 ns).

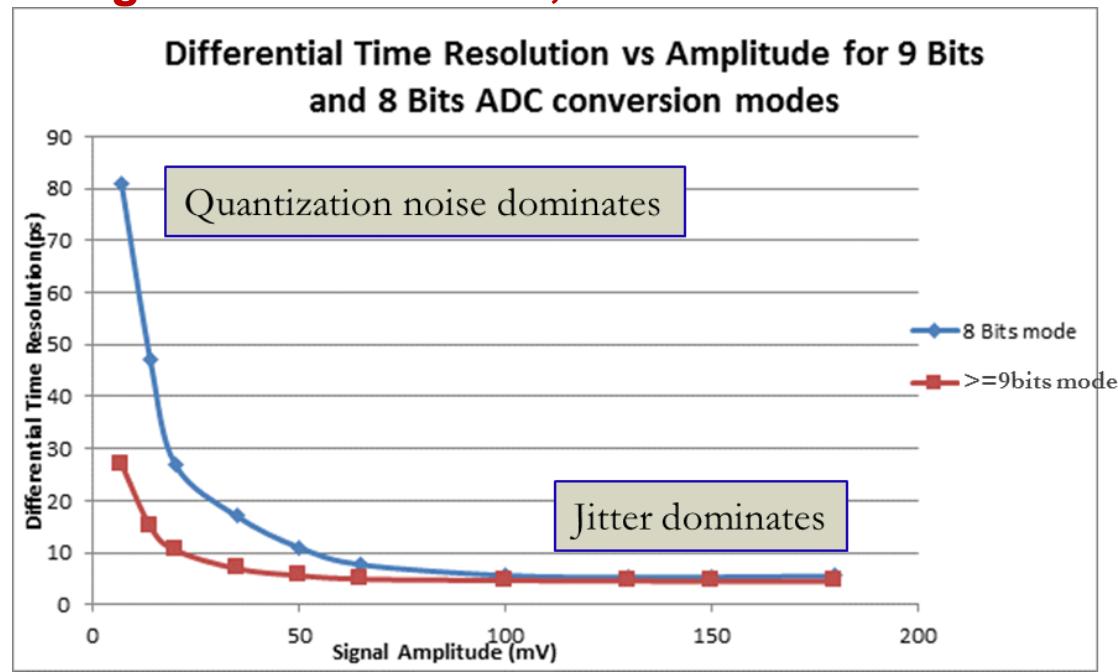
→ decrease of channel dead time

- The quantization noise could affect the timing precision especially for small signals

But $Q_N = 400\mu V_{rms}$ for 9bit mode negligible compared to SAMPIC noise = $950\mu V_{rms}$

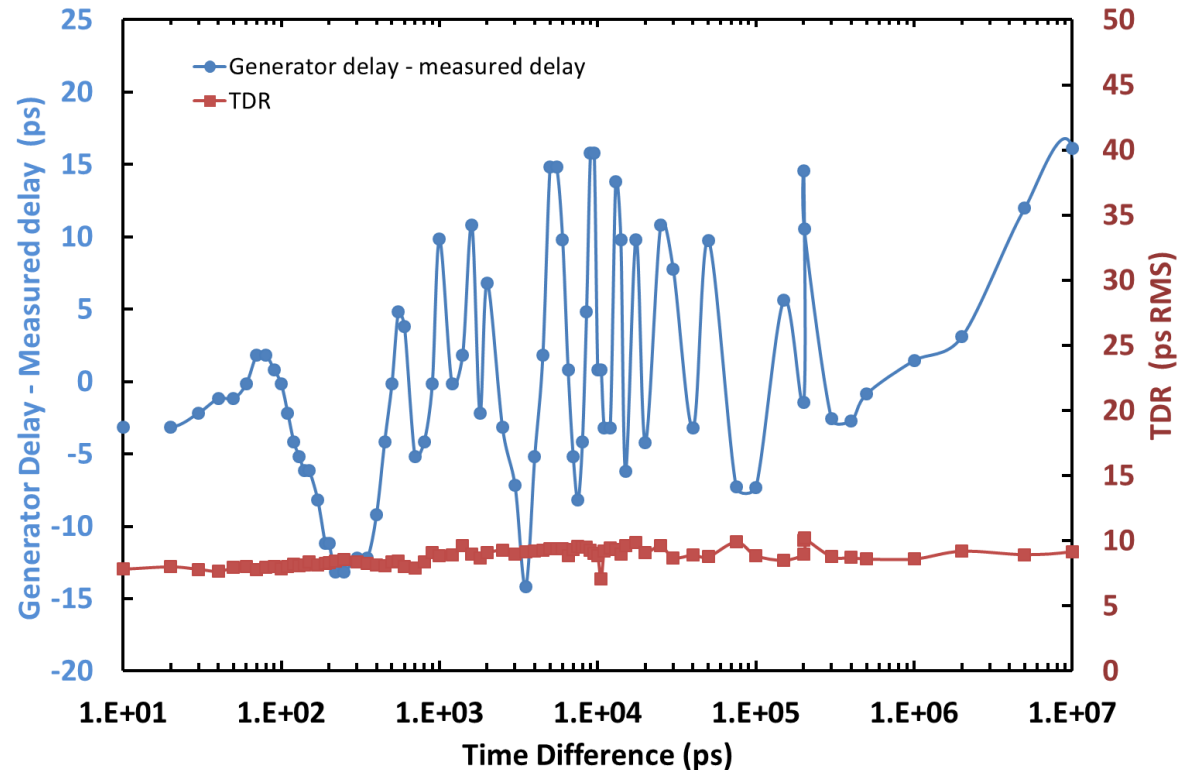
- **As expected no significant change measured for 11, 10 and 9-bit modes**

**No degradation on timing
for pulses above 100mV for
8 bits**



EXPLORING LARGER DELAYS: TOWARD AN « ABSOLUTE » TIME MEASUREMENT

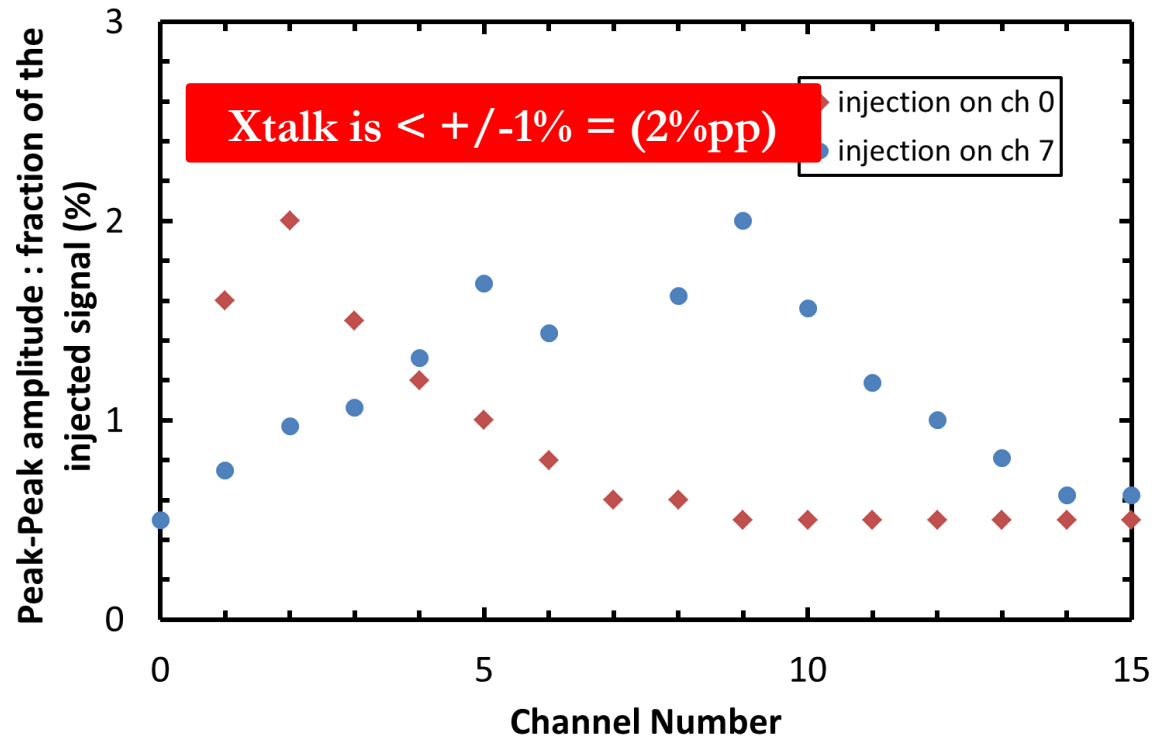
- Now we use 2 channels of a TEK AFG 3252 arbitrary waveform generator and program their relative delay (10-ps steps)
- Slower than the previous generator (2.5ns risetime min)
- TEK AFG 3252 is specified for an absolute precision of few 10 ps delay and a 100ps jitter
=> Measurements are clearly MUCH MORE better



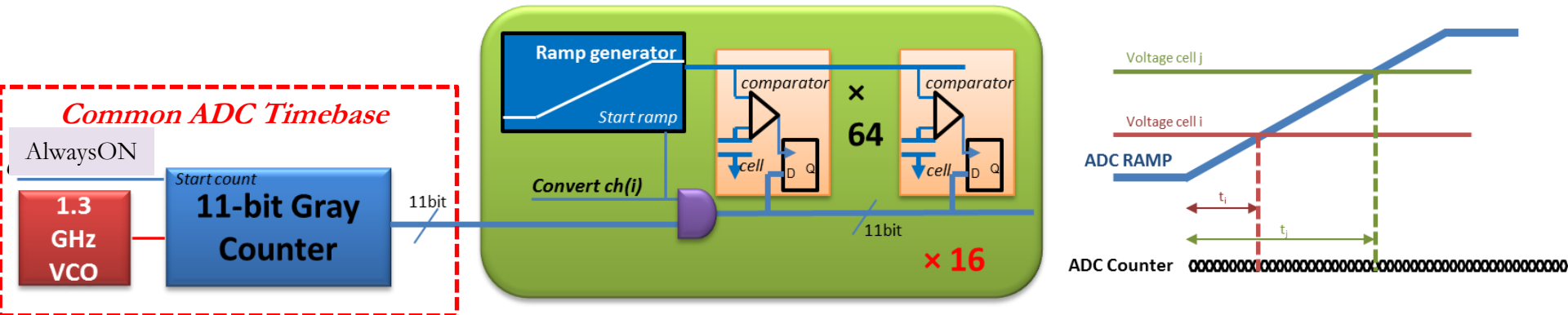
- TDR is < 10ps rms, even for delays up to 10 μ s => **1-ppm RESOLUTION**
- Difference between AFG programmed delay and measured value is < +/-15ps

SAMPIC_V0: XTALK MEASUREMENT

- 800mV, 1ns FWHM, 300ps risetime and falltime injected on **channel 7 (blue)**
- Signal measured on the other channels
- Xtalk = derivative and decrease as the distance to the injection channel
- Xtalk signal is bipolar with \sim equal positive and negative lobe
- Similar plot, but shifted if injection in another channel (**red**)



WILKINSON ADC WITH AUTO-CONVERSION MODE



- **When triggered, each channel launches its auto-conversion.**
 - When ramp starts, the value of the continuously running counter is sampled in a dedicated channel register
 - When the ramp crosses the cell voltage => the current value of the counter is stored in the cell register (ramp offset).
 - **As soon as all discriminators of the channel have fired, Analog to Digital conversion of the channel is over => optimization of dead time**
 - During readout, the ramp offset is read before the channel waveform samples.

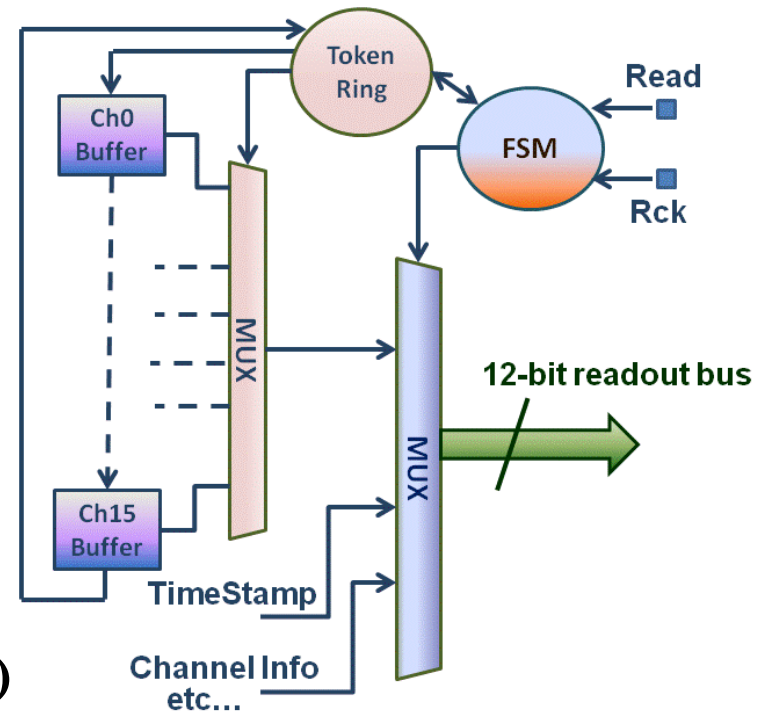
In “auto-conversion” mode , the ramp offset will be subtracted from the value of the waveform samples.

READOUT PHILOSOPHY

- Readout driven by **Read** and **Rck** signals => **controlled by FPGA**
- Data is read **channel by channel** as soon it is available
- Rotating **priority mechanism** to avoid reading always the same channel at high rate
- **Optional Region Of Interest readout** to reduce the dead time (**nb of cells read can be chosen dynamically**)
- Readout of converted data through a 12-bit parallel LVDS bus including:

- Channel Identifier, Timestamps, Trigger Cell Index
- The cells (all or a selected set) of a given channel sent sequentially
- Standard readout at 2 Gbits/s

=> **Rate > 2 Mevts/s (full waveform)**



- **Channel is not in deadtime during readout, only during conversion** (data register is really a buffer stage)

CALIBRATION PHILOSOPHY

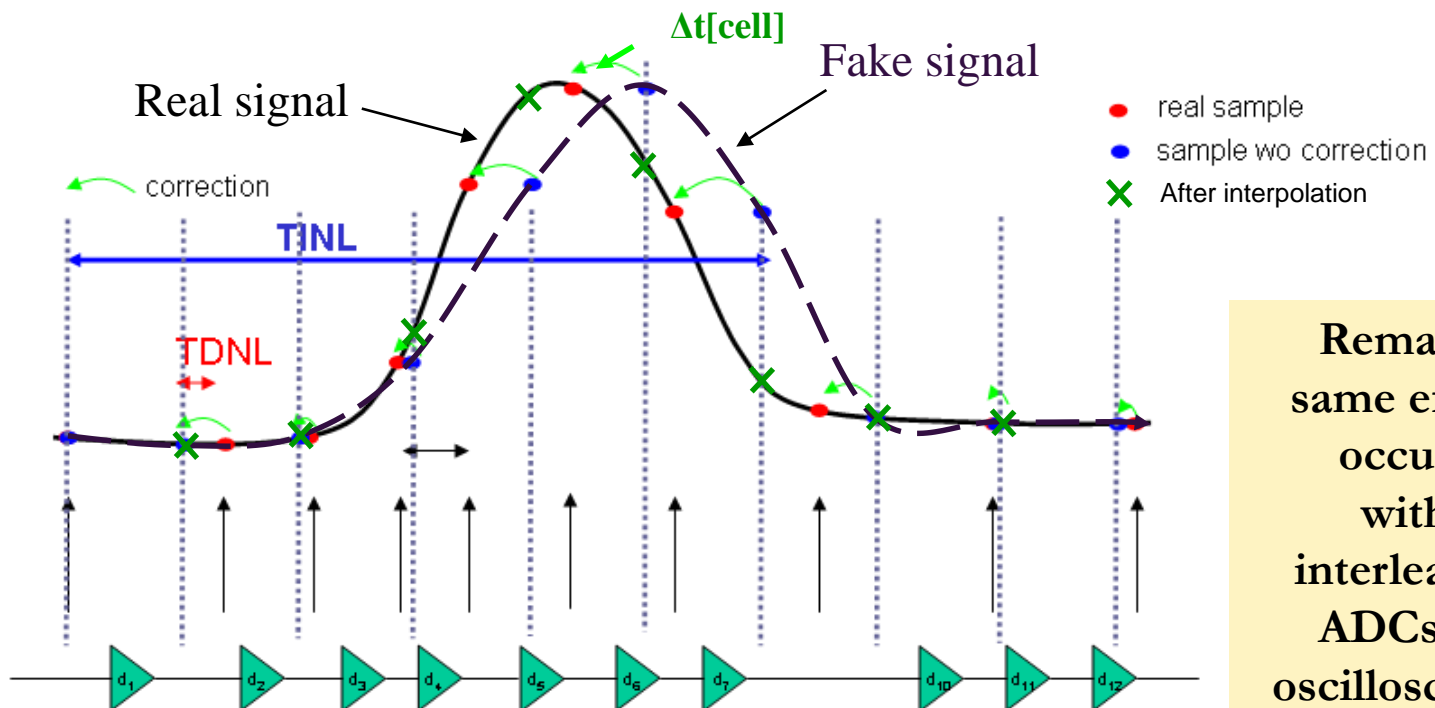
- SCAs-based chips exhibit reproducible non-idealities which can be easily corrected after calibration:
 - The goal is to find the set with the **best performance/complexity ratio**.
 - But also to find the right set for the **highest level of performance**.
- SAMPIC actually offers very good performance with only two types of simple calibrations :
 - **Amplitude: cell pedestal and gain** (linear or **parabolic** fit) => DC ramp
 - **Time: INL** (one offset per cell) => use of a **simple sinewave** (see backup)
 - This leads to a limited volume of standard calibration data (**4 to 6** Bytes/cell/sampling frequency => **5 to 8** kBytes/chip/sampling frequency) => can be stored in the on-board EEPROM (1Mbit).
- These simple corrections could even be applied **in the FPGA**.
- Highest level calibrations permit debugging the chip and pushing the performance to its limit (still unknown).

TIMING NON-LINEARITIES

- Dispersion of single delays => **time DNL**
- **Cumulative effect** => **time INL**. Gets worse with delay line length.
- **Systematic & fixed effect** => non equidistant samples => Time Base Distortion

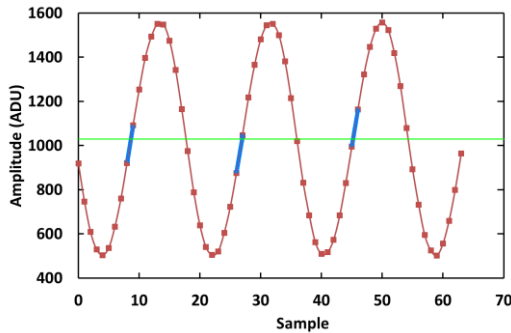
If we can measure it => we can correct it !

But calibration and even more correction have to remain “simple”.



Remark:
same effect
occurs
with
interleaved
ADCs in
oscilloscopes

TIME INL CALIBRATION AND CORRECTION



Method we introduced in 2009 and used since for our analog memories, assuming that a sine wave is nearly linear in its zero crossing region: **much more precise than statistical distribution**

- Search of zero-crossing segments of a free running asynchronous sine wave

=> length[position]

- Calculate the average amplitude for zero-crossing segment for each cell.

- Renormalize (divide by average amplitude for all the cells and multiply by the clock period/number of DLL steps)

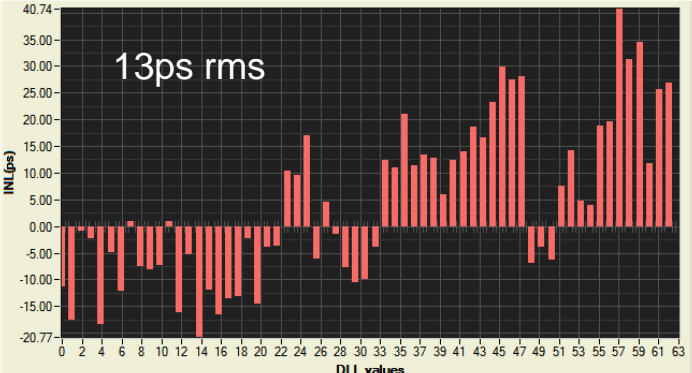
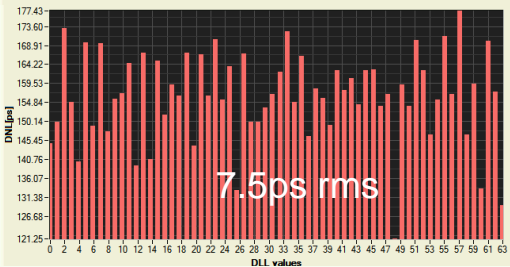
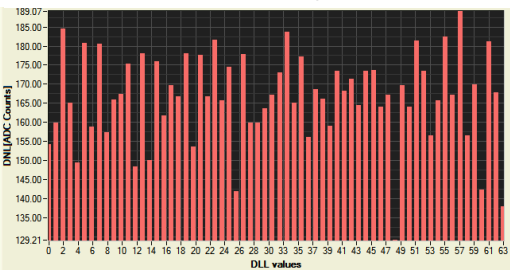
=> time duration for each step = “time DNL”

- Integrate this plot:

=> Fixed Pattern Jitter = correction to apply to the time of each sample = “time INL”

Time INL correction:

- **Simple addition** on T_{sample}
- Also permits the calculation of real equidistant samples by interpolation or digital filtering.

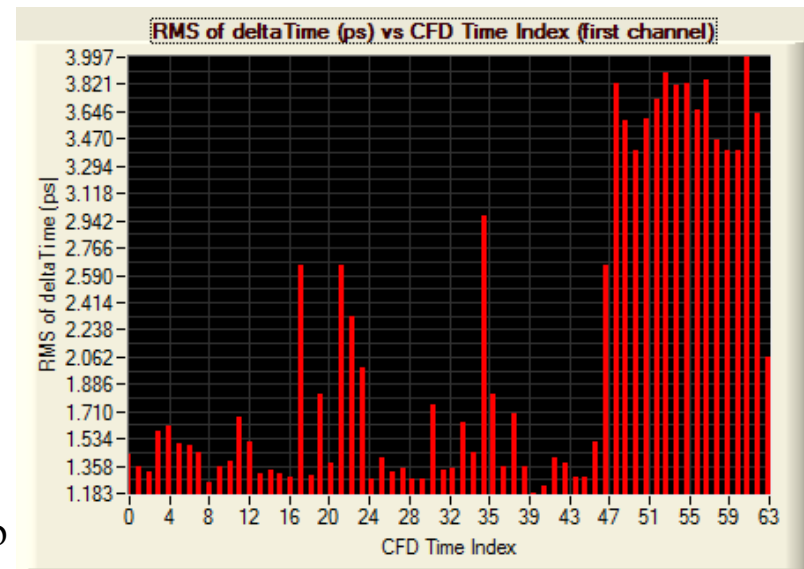


TRICKS FOR UNDERSTANDING RESOLUTION

- This is how we measure the contributions to the resolution:
we run at 6.4 GS/s, send two 500 mV pulses separated by 2.5 ns to two channels:

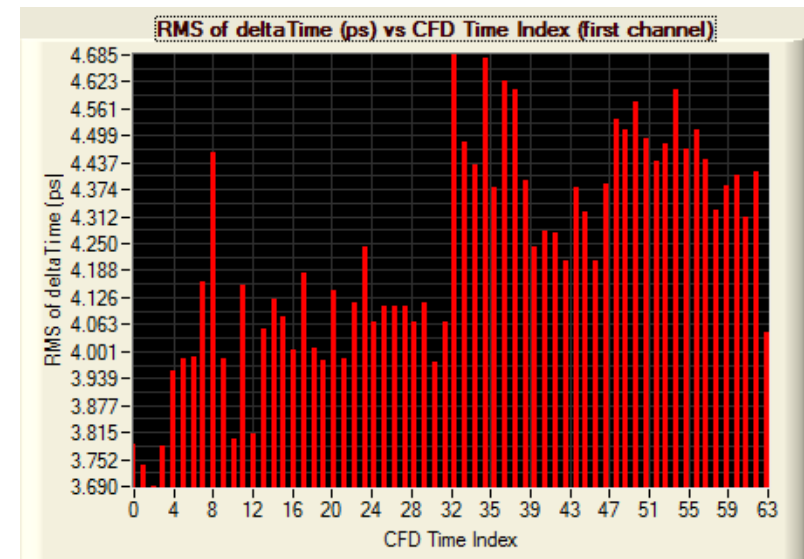
1. of the same mezzanine
2. of two different mezzanines

Same chip

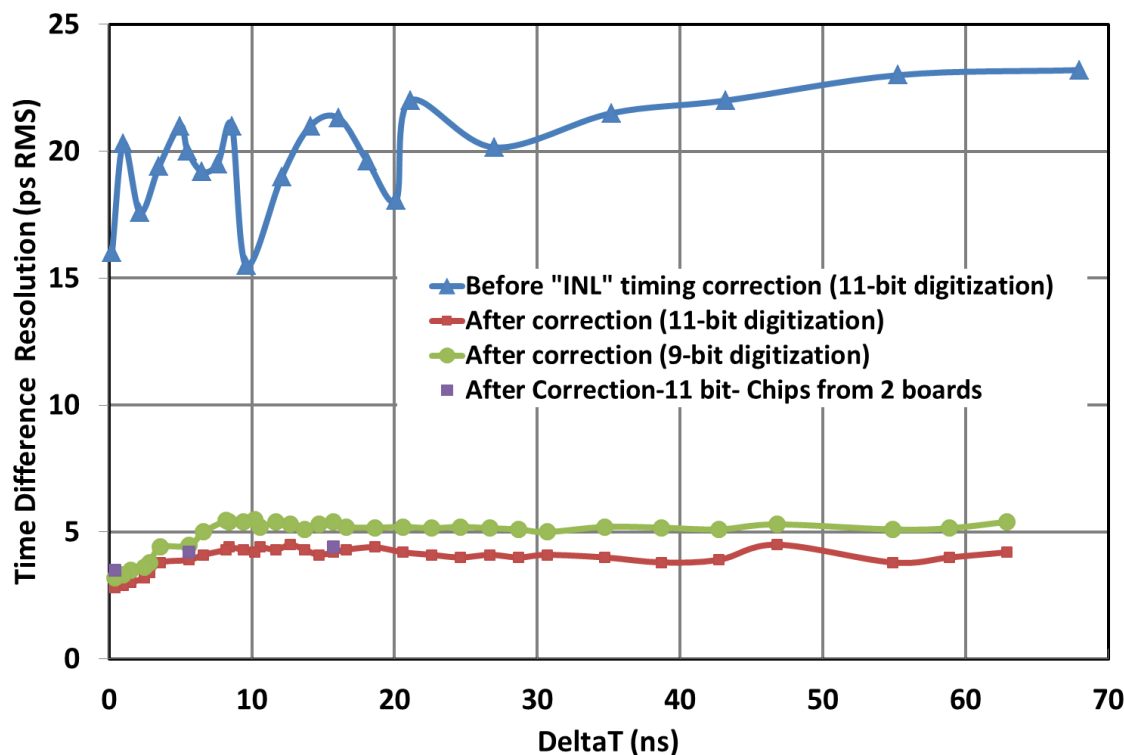
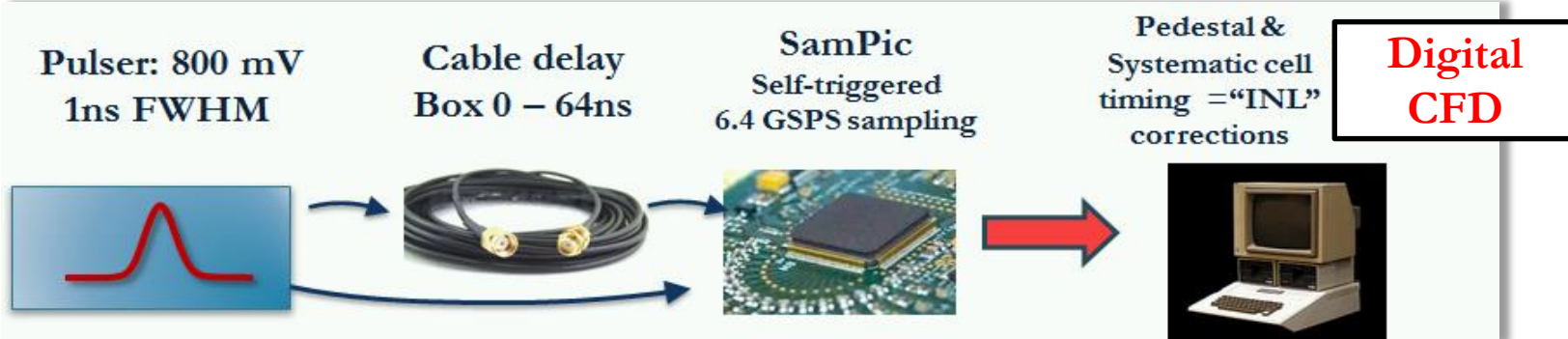


- From this we can extract that **the jitter contribution is:**
- ~ 1.5 ps rms from the DLL
- ~ 1.8 ps rms from the clock distribution on the motherboard
- ~ 2.4 ps rms from the clock distribution on the mezzanine

Different chips



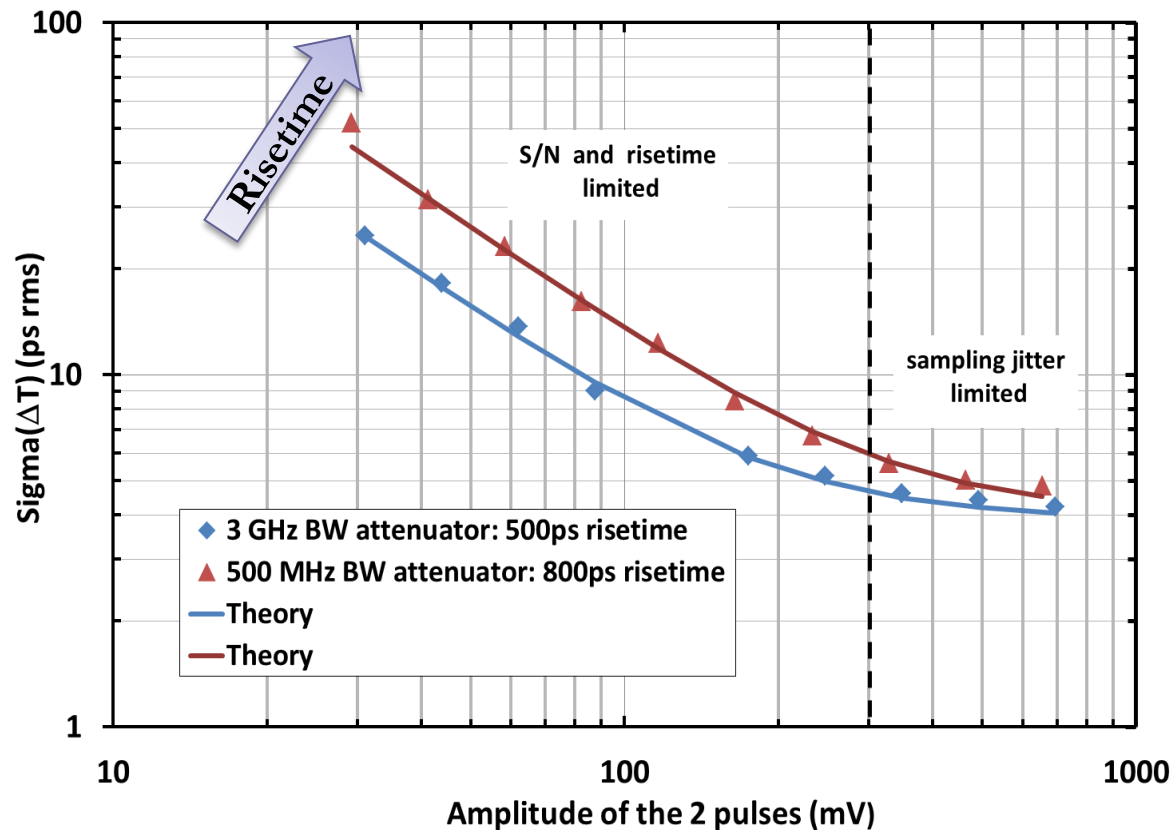
ΔT RESOLUTION VS DELAY



- TDR < 25 ps RMS before time cor.
 - TDR < 5 ps RMS after time cor.
 - TDR is constant after $\Delta T = 10$ ns
 - Unchanged for 2 chips from 2 different mezzanines (same clk source but different DLLs and on-chip clock path)
- => Channel single pulse timing resolution is < 3.5 ps RMS ($5 \text{ ps} / \sqrt{2}$)
- For these large pulses TDR is worst by only 1ps RMS in 9-bit mode (digitization time divided by 4)

TIMING RESOLUTION VS AMPLITUDE & RISETIME

1-NS FWHM - 15 NS DELAY, DIGITAL CFD ALGORITHM



Measurements consistent with the theoretical formula:

$$\sigma(\Delta t) = \sqrt{2} \times \sqrt{\sigma_j^2 + \alpha \times \left(\frac{\sigma_n}{\text{Slope}} \right)^2}$$

Assuming: :

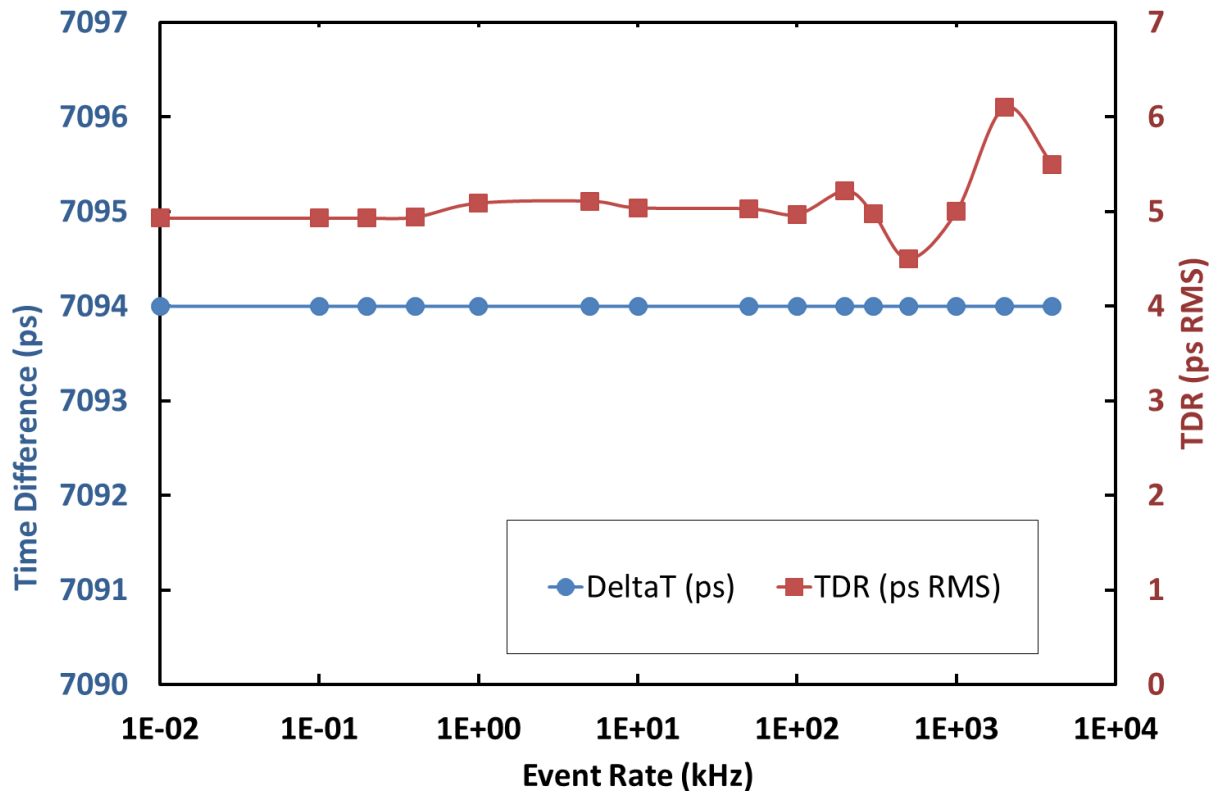
- * Voltage noise $\sigma_n = 1.1$ mV RMS
 - * Sampling jitter $\sigma_j = 2.8$ ps RMS
 - * $\alpha = 2/3$ (theory for perfect CFD)
- [arXiv:1606.05541v1](https://arxiv.org/abs/1606.05541v1)

- **2 zones: sampling jitter or S/N limited zones.**
- **TDR < 8 ps rms for pulse amplitudes > 100mV**
- TDR < 20 ps rms for pulse amplitudes > 40 mV
- Can be improved by using mores samples (if feasible and uncorrelated) since dCFD uses only 2 samples

TIMING RESOLUTION VS RATE

1ns FWHM, 400ps risetime, 0.7V signals sent to 2 channels of SAMPIC

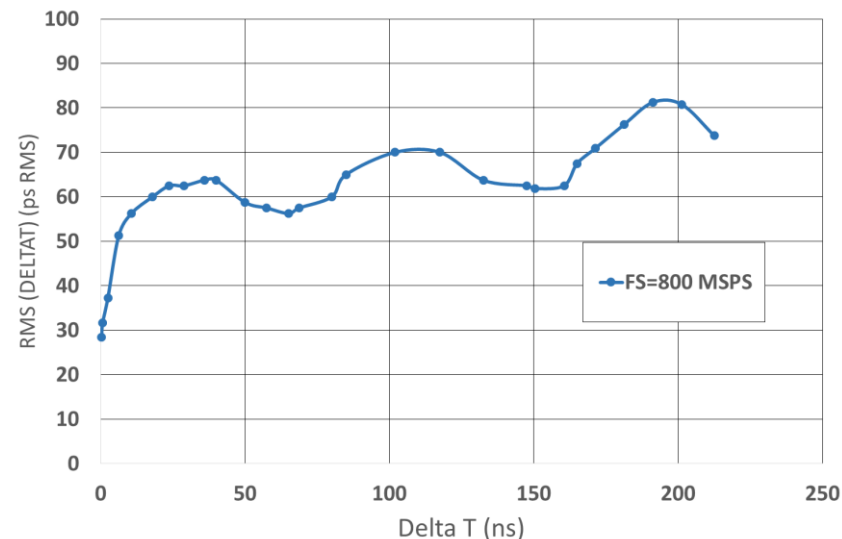
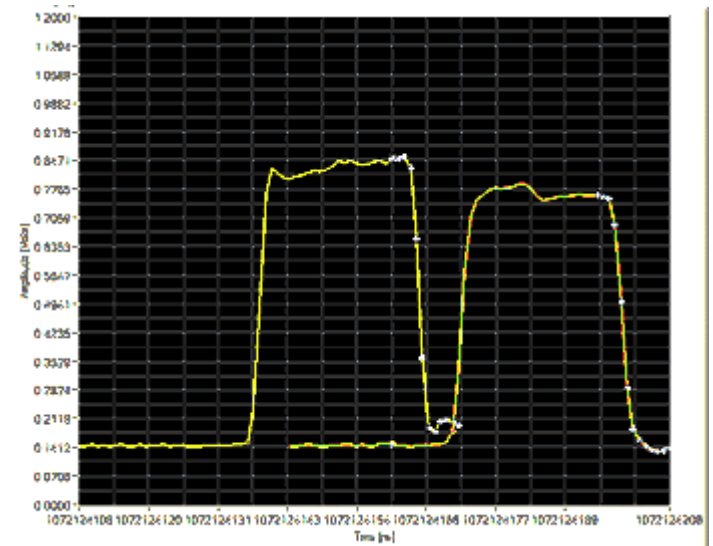
- 7.1ns delay by cable, 6.4 GS/s, 11-bit mode, 64 samples, both INLs corrected
- Rate is progressively increased.



The measured delay and its resolution are stable for channel rates up to 2 MHz

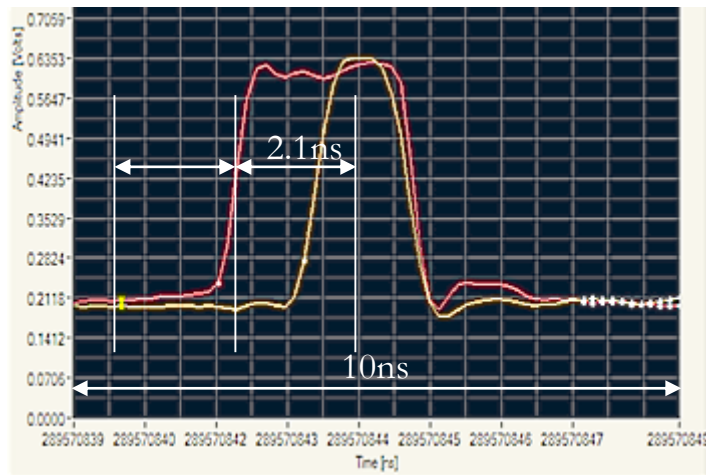
NEW in SAMPIC V3: 800 MS/s mode

- Was not possible in the previous SAMPIC versions
- The 64 cells cover a 80 ns window with 1.25 ns steps
- Tested here with an external clock with unknown jitter + cables that degrades the slopes for larger delays
- < 40ps RMS resolution for a single signal
- Could be usefull for applications with slower detectors (semiconductors, moderate-speed light detector)



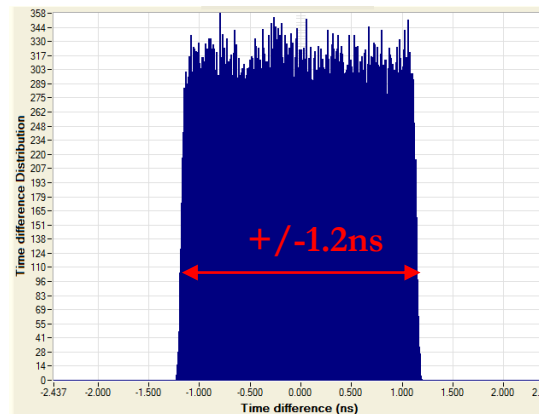
CENTRAL TRIGGER/ COINCIDENCE

- Each channel can be triggered by the CENTRAL TRIGGER: can be the **OR**, or a **Coincidence of ≥ 2 or ≥ 3 channels**
- Coincidence Gate generated by an asynchronous delay as previously described.
- **Only 1ns of extra latency on trigger decision**
- Test below using 2 signals ($\gg 1\text{MHz}$) with random phases sent to 2 channels with 1.2 or 2.1ns coincidence gate.

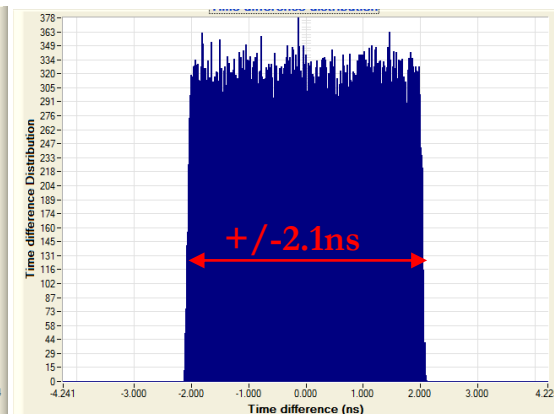


1 of the couples of signals digitized.
2.1 ns gate @ 6.4 GSPS

TimeDifference histogram (from the digitized waveform)



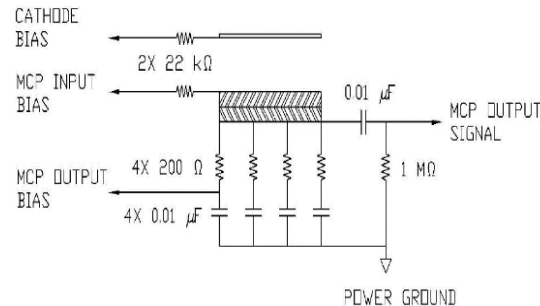
« 1.2ns » coincidence gate



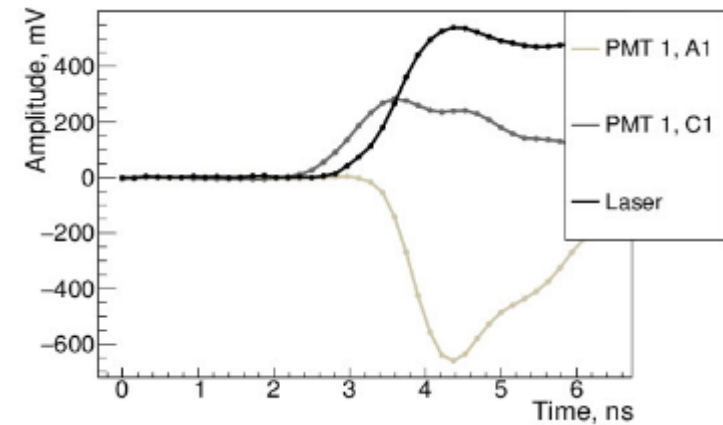
« 2.1ns » coincidence gate

SCAN TEST OF MCP-PMT

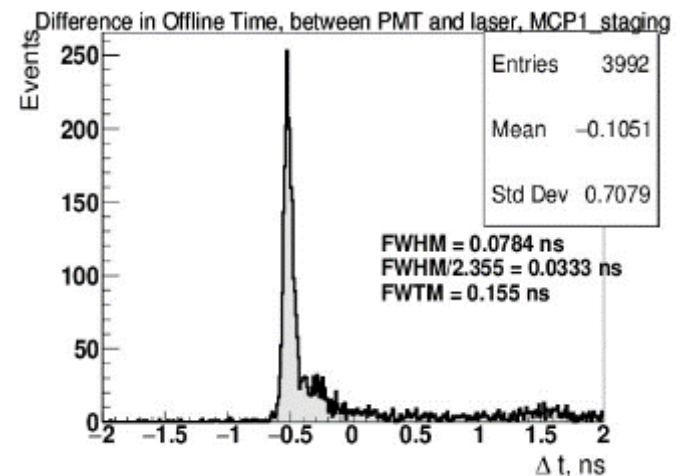
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- PLANACON XP85012 used for CALIPSO/PECHE
- 53 mm x 53 mm, 64 anodes → 16 channels (groups of 4 anodes)
- Rise time 0.6 ns, pulse width 1.8 ns
- Use pulsed laser PILAS in the **single-photon mode**
- Beam duration 20ps collimated by a pin-hole with a diameter 0.4 mm
- Use automatic XZ staging station Zaber.
- Step size 1 mm , Precision ~10 μm
- **SAMPIC in two-level trigger coincidence mode (anode & laser)**
- **Data taking: rate of ~50 kHz**
- 2 sec / per stage, 0.5 sec / move
- **Total scan time ~2 hours**



Difference in time between laser trigger and anode signal



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Measurements of timing resolution of ultra-fast silicon detectors with the SAMPIC waveform digitizer

D. Breton^a, V. De Cacqueray^{b,1}, E. Delagnes^b, H. Grabas^c, J. Maalmi^a, N. Minafra^{d,e,2}, C. Royon^f, M. Saimpert^{b,*}

^a CNRS/IN2P3/LAL Orsay, Université Paris-Saclay, F-91898 Orsay, France

^b IRFU, CEA, Université Paris-Saclay, F-91191 Gif-sur-Yvette, France

^c Santa Cruz Institute for Particle Physics UC Santa Cruz, CA 95064, USA

^d Dipartimento Interuniversitario di Fisica di Bari, Bari, Italy

^e CERN, Geneva, Switzerland

^f University of Kansas, Lawrence, USA



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ABSTRACT

The SAMPIC for Picosecond time (SAMPIC) chip has been designed by a collaboration including CEA/IRFU/SEDI, Saclay and CNRS/LAL/SERDI, Orsay. It benefits from both the quick response of a time to digital converter and the versatility of a waveform digitizer to perform accurate timing measurements. Thanks to the sampled signals, smart algorithms making best use of the pulse shape can be used to improve time resolution. A software framework has been developed to analyse the SAMPIC output data and extract timing information by using either a constant fraction discriminator or a fast cross-correlation algorithm. SAMPIC timing capabilities together with the software framework have been tested using pulses generated by a signal generator or by a silicon detector illuminated by a pulsed infrared laser. Under these ideal experimental conditions, the SAMPIC chip has proven to be capable of timing resolutions down to 4 ps with synthesized signals and 40 ps with silicon detector signals.

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Study of timing characteristics of a 3 m long plastic scintillator counter using waveform digitizers

A. Blondel^a, D. Breton^b, A. Dubreuil^a, A. Khotyantsev^c, A. Korzenev^{a,2}, J. Maalmi^b, A. Mefodev^c, P. Mermod^{a,2}, E. Noah^a

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Abstract

A plastic scintillator bar with dimensions 300 cm × 2.5 cm × 11 cm was exposed to a focused muon beam to study its light yield and timing characteristics as a function of position and angle of incidence. The scintillating light was read out at both ends by photomultiplier tubes whose pulse shapes were recorded by waveform digitizers. Results obtained with the WAVECATCHER and SAMPIC digitizers are analyzed and compared. A discussion of the various factors affecting the timing resolution is presented. Prospects for applications of plastic scintillator technology in large-scale particle physics detectors with timing resolution around 100 ps are provided in light of the results.

<http://arxiv.org/abs/1604.02385>

<http://arxiv.org/abs/1610.05667>